

**SEMICON
EUROPA**

FORWARD
AS ONE

An *OmniVariate* Approach to Semiconductor Reliability

**Reliability & Quality Improvement for
Aerospace and Automotive Applications**

Wes Smith - Galaxy Semiconductor
November 17, 2022



Abstract

As the number and complexity of electronic parts increases with every vehicle, the demands for reliability continually increase. This is even more acute when deploying advanced materials such as SiC and GaN to address the ever more stringent demands for electric powertrains.

An advanced statistical screening approach is proposed for the purpose of identification of electronic parts that have an elevated risk of field failure. A comparison is made between the proposed Omnivariate approach, industry-standard DPAT, and more commonly recognized multivariate methods such as Mahalanobis Distance and Hotelling T^2 , which tend to provide less useful information as the number of monitored parameters exceeds a few hundred.

A few examples from known RMA devices on Silicon CMOS manufacturing are used for demonstration.

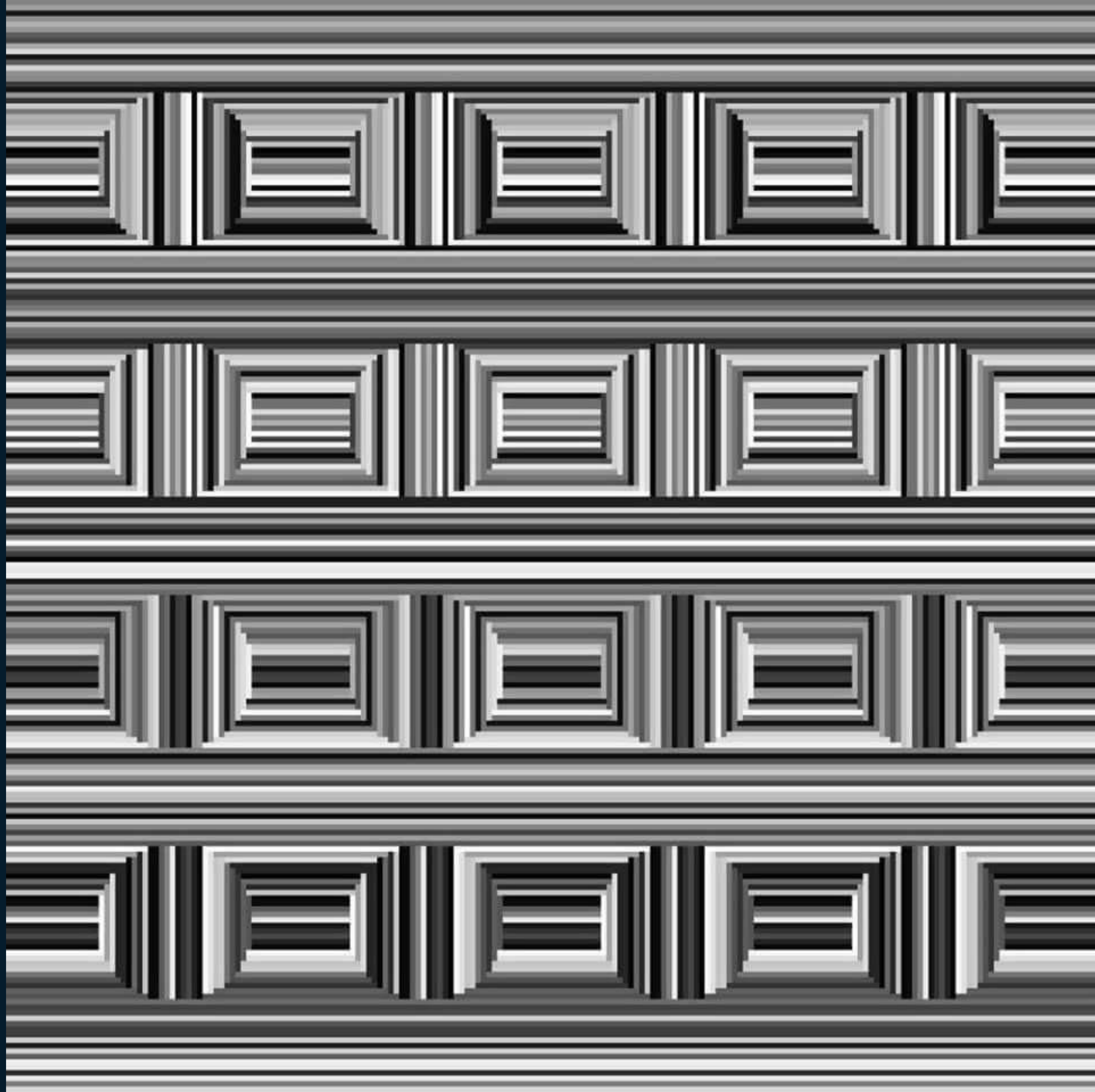


Image Credit:
Mike Battista, Cambridge Brain Sciences
<https://www.cambridgebrainsciences.com/>

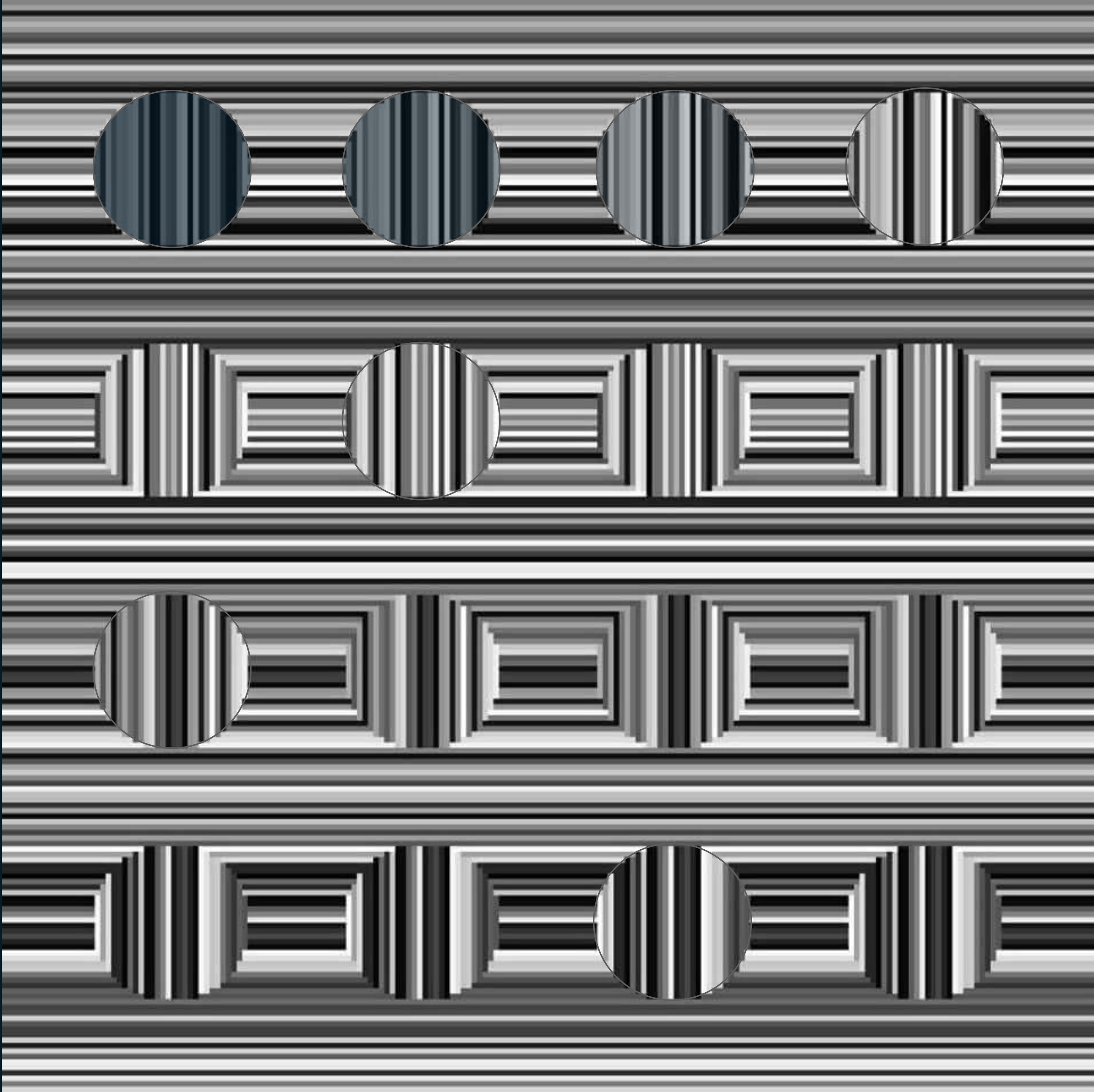
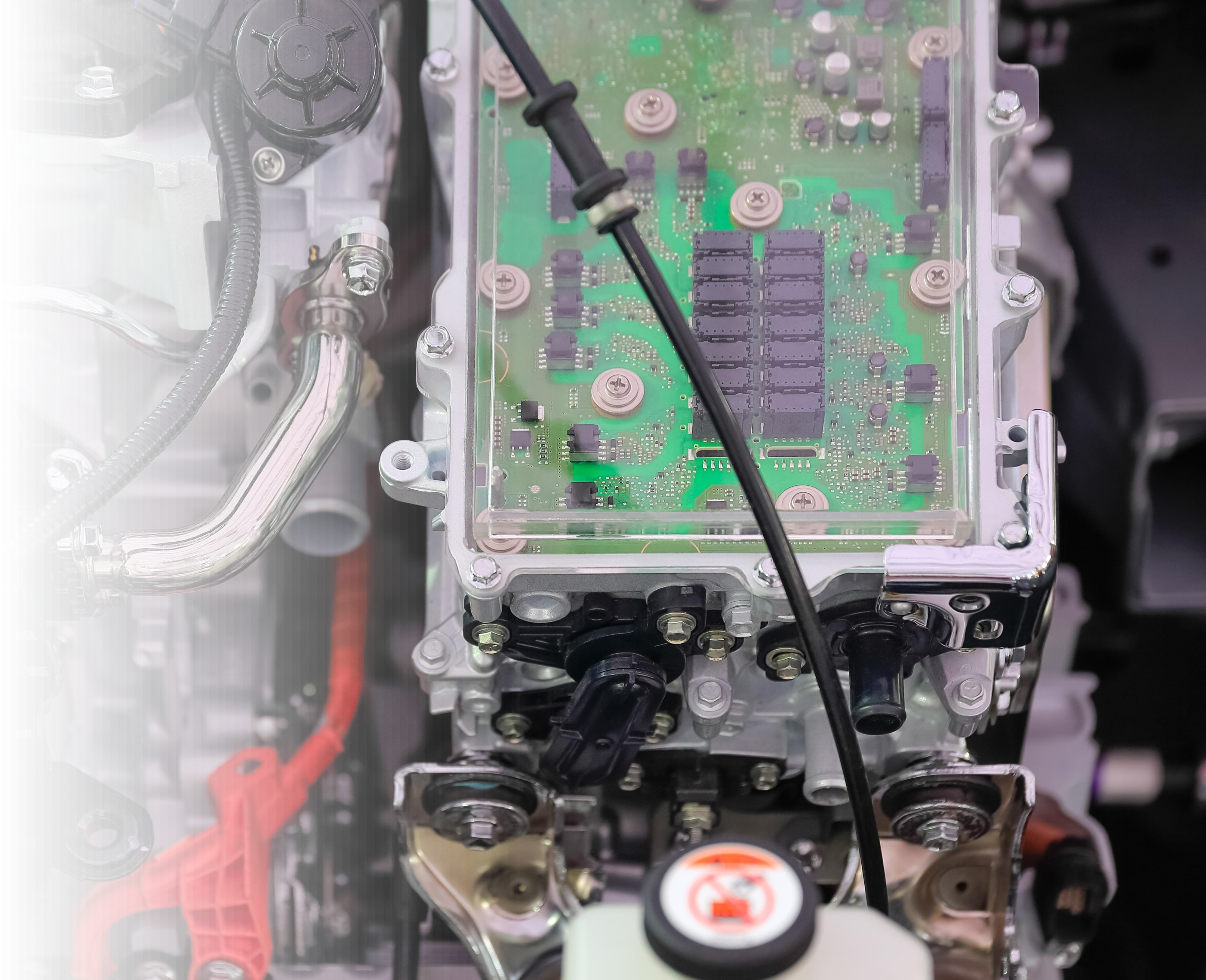
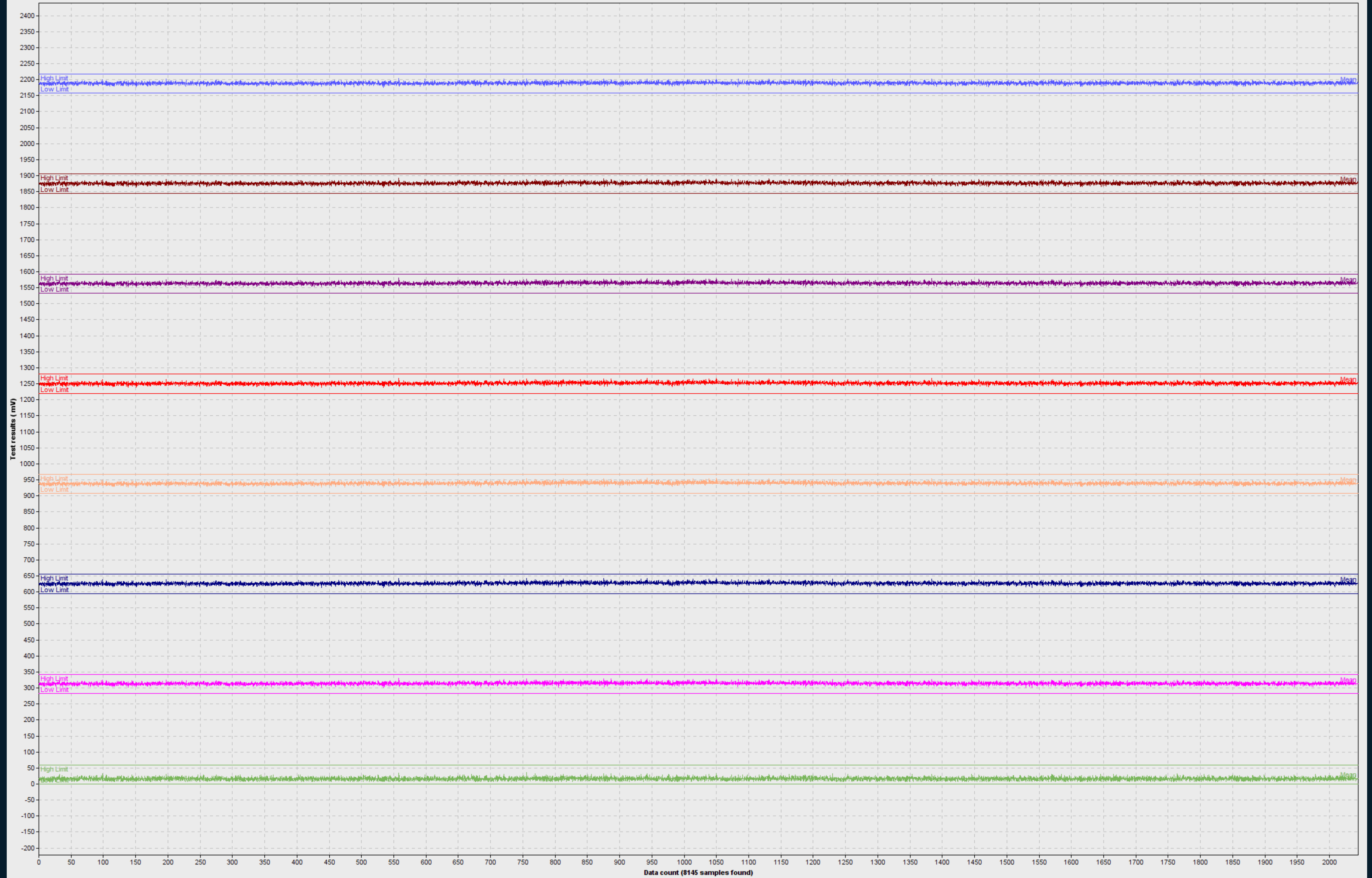


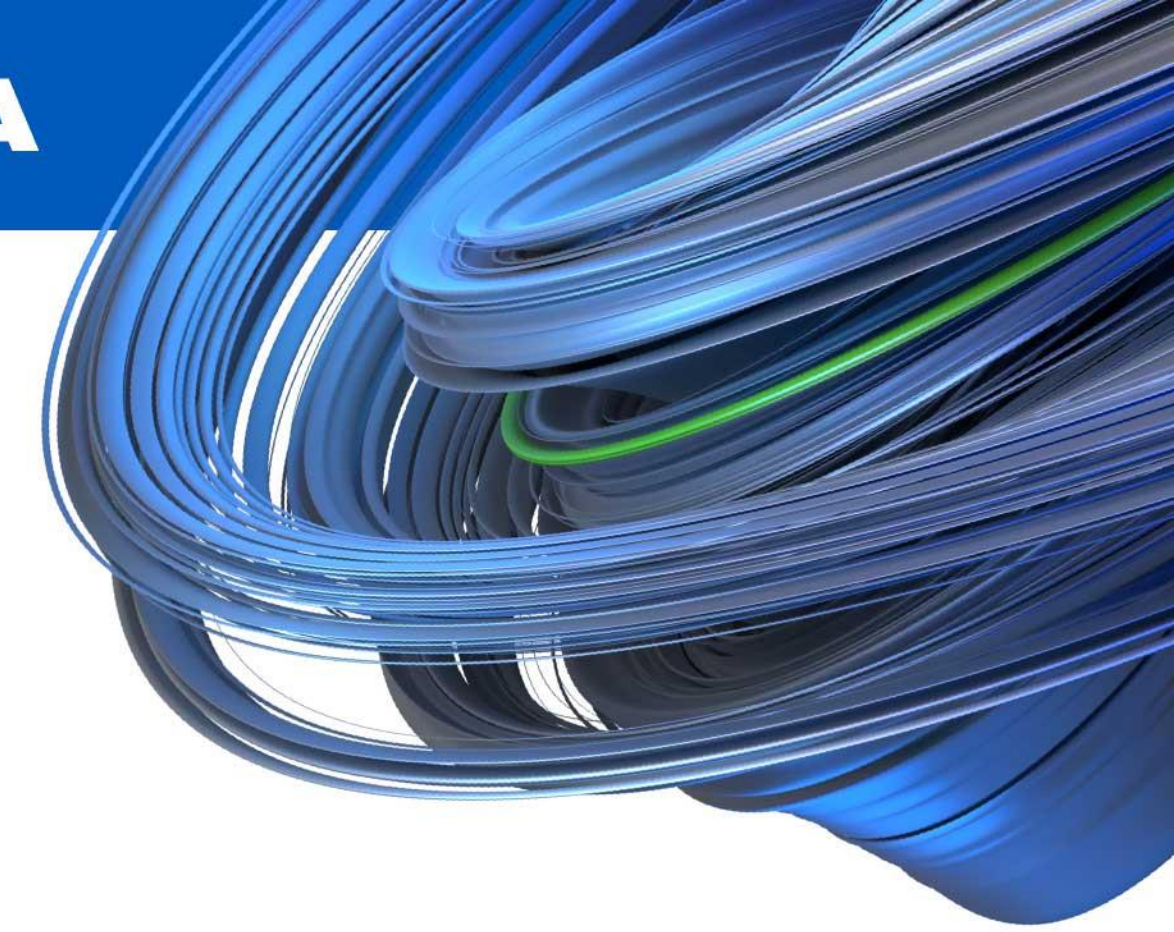
Image Credit:
Mike Battista, Cambridge Brain Sciences
<https://www.cambridgebrainsciences.com/>

- **Once upon a time in Vokalia...**
- **50 RMA**
- **Devices.**
- **1 Angry Customer**

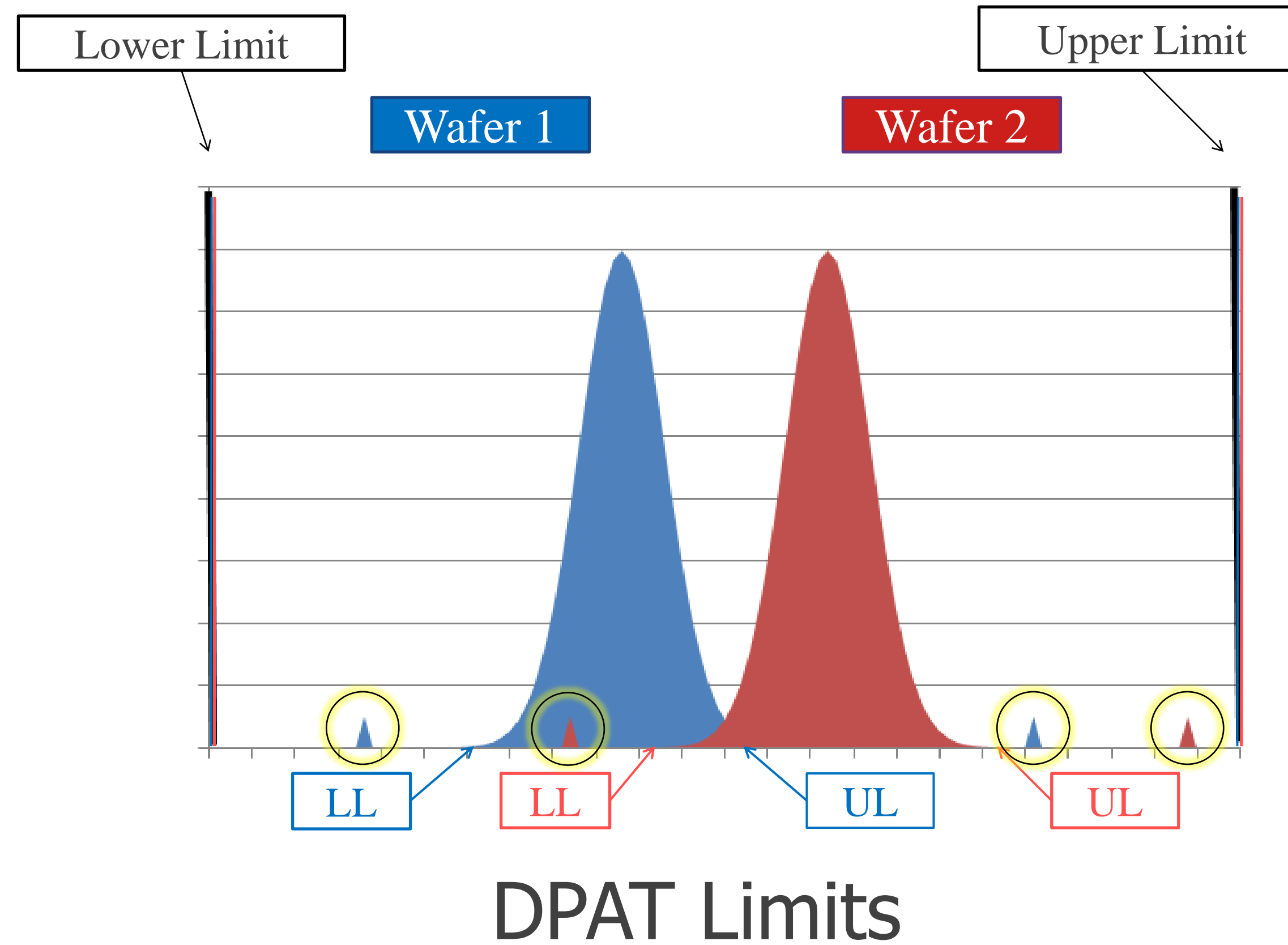


Test	Name	Type	Low L.	High L.	Shape	Source	Execs	Fails	Fails %	Flow ID	Mean	Sigma	3xSigma	Min	Max	Cpk	Cpl	Cpu	Yield	Skew	Kurtosis	P2.5%	P50% - Median	P97.5%	IQR	IQR SD
400		P	0.0 V	60 mV	Unknown	Samples	100281	3	0.00 %	1	15.957 mV	14.2497 mV	42.749 mV	5.493 mV	2.4973 V	0.3733	0.3733	1.03	100.00 %	156.592	27185.6	8.0785 mV	15.783 mV	24.8755 mV	6.3295 mV	4.69199 mV
401		P	0.2825 V	0.3425 V	Gaussian	Samples	100281	3	0.00 %	2	314.435 mV	12.458 mV	37.3739 mV	299.443 mV	2.49731 V	0.7509	0.8545	0.7509	100.00 %	159.271	27809.3	307.119 mV	314.371 mV	321.621 mV	4.97848 mV	3.6905 mV
402		P	0.595 V	0.655 V	Gaussian	Samples	100281	3	0.00 %	3	627 mV	10.8791 mV	32.6372 mV	611.158 mV	2.49709 V	0.6579	0.9805	0.8579	100.00 %	150.205	25718.8	619.507 mV	626.936 mV	634.472 mV	5.13101 mV	3.80356 mV
403		P	0.9075 V	0.9675 V	Gaussian	Samples	100281	3	0.00 %	4	939.539 mV	9.31381 mV	27.9414 mV	923.24 mV	2.4974 V	1.00	1.15	1.00	100.00 %	137.997	22970.1	931.97 mV	939.479 mV	947.087 mV	5.19753 mV	3.85287 mV
404		P	1.22 V	1.28 V	Gaussian	Samples	100281	4	0.00 %	5	1.25181 V	7.79812 mV	23.3944 mV	1.23599 V	2.49718 V	1.20	1.36	1.20	100.00 %	119.706	19002.9	1.24418 V	1.25177 V	1.25936 V	5.20802 mV	3.86065 mV
405		P	1.5325 V	1.5925 V	Gaussian	Samples	100281	4	0.00 %	6	1.5644 V	6.34684 mV	19.0405 mV	1.54764 V	2.49731 V	1.48	1.68	1.48	100.00 %	92.7933	13530.6	1.55685 V	1.56438 V	1.57185 V	5.16701 mV	3.83025 mV
406		P	1.845 V	1.905 V	Gaussian	Samples	100281	3	0.00 %	7	1.87661 V	5.02956 mV	15.0887 mV	1.85955 V	2.49742 V	1.88	2.09	1.88	100.00 %	1.86919 V	1.87659 V	1.86919 V	1.87659 V	1.88391 V	5.06592 mV	3.75531 mV
407		P	2.1575 V	2.2175 V	Gaussian	Samples	100281	3	0.00 %	8	2.18921 V	4.01594 mV	12.0478 mV	2.17249 V	2.49742 V	2.35	2.63	2.35	100.00 %	12.5527	941.553	2.18197 V	2.18921 V	2.19631 V	4.94695 mV	3.66712 mV
408		P	2.47 V	2.53 V	Gaussian	Samples	100281	0	0.00 %	9	2.50088 V	3.87857 mV	11.6357 mV	2.48285 V	2.5177 V	2.50	2.65	2.50	100.00 %	-0.0261686	0.0265532	2.49323 V	2.5009 V	2.50842 V	5.25117 mV	3.89264 mV
409		P	2.7825 V	2.8425 V	Gaussian	Samples	100281	3	0.00 %	10	2.81362 V	4.18855 mV	12.5656 mV	2.48504 V	2.82919 V	2.30	2.48	2.30	100.00 %	-13.8451	1068.88	2.80612 V	2.81365 V	2.82099 V	5.14007 mV	3.81028 mV
410		P	3.095 V	3.155 V	Gaussian	Samples	100281	3	0.00 %	11	3.12585 V	5.1235 mV	15.3705 mV	2.48502 V	3.14171 V	1.90	2.01	1.90	100.00 %	-57.1826	7094.56	3.11844 V	3.12589 V	3.13315 V	5.07593 mV	3.76274 mV
411		P	3.4075 V	3.4675 V	Gaussian	Samples	100281	4	0.00 %	12	3.43854 V	6.40188 mV	19.2056 mV	2.48477 V	3.45444 V	1.51	1.62	1.51	100.00 %	-97.3443	14423	3.43115 V	3.43858 V	3.44582 V	5.04899 mV	3.74277 mV
412		P	3.72 V	3.78 V	Gaussian	Samples	100281	4	0.00 %	13	3.75081 V	7.844 mV	23.532 mV	2.48499 V	3.76679 V	1.24	1.31	1.24	100.00 %	-124.25	19970.4	3.74343 V	3.75087 V	3.75811 V	5.02396 mV	3.72421 mV
413		P	4.0325 V	4.0925 V	Gaussian	Samples	100281	4	0.00 %	14	4.06362 V	9.37727 mV	28.1318 mV	2.48492 V	4.07976 V	1.03	1.11	1.03	100.00 %	-141.394	23726.8	4.05633 V	4.0637 V	4.07091 V	4.99916 mV	3.70583 mV
414		P	4.345 V	4.405 V	Gaussian	Samples	100281	4	0.00 %	15	4.37602 V	10.9556 mV	32.8668 mV	2.48466 V	4.39169 V	0.8816	0.9439	0.8816	100.00 %	-152.653	26279.1	4.36878 V	4.3761 V	4.38325 V	4.95005 mV	3.66942 mV
415		P	4.6575 V	4.7175 V	Gaussian	Samples	100281	6	0.01 %	16	4.68901 V	14.3586 mV	43.0758 mV	2.48475 V	4.70495 V	0.6613	0.7316	0.6613	99.99 %	-143.167	21915	4.68195 V	4.68912 V	4.69615 V	4.87232 mV	3.6118 mV
Test	Name	Type	Low L.	High L.	Shape	Source	Execs	Fails	Fails %	Flow ID	Mean	Sigma	3xSigma	Min	Max	Cpk	Cpl	Cpu	Yield	Skew	Kurtosis	P2.5%	P50% - Median	P97.5%	IQR	IQR SD
416		P	4.62 V	4.69 V	Unknown	Samples	100281	5	0.00 %	17	4.67306 V	26.562 mV	79.6861 mV	-599 uV	4.68142 V	0.2126	0.6658	0.2126	100.00 %	-168.656	29139.5	4.6696 V	4.67329 V	4.6765 V	2.388 mV	1.7702 mV
417		P	-3.0 LSB	3.0 LSB	Bi-Modal (clear modes)	Samples	100281	10	0.01 %	18	-99.4087 mLSB	5.42086 LSB	16.2626 LSB	-1.67579 KLSB	7.69336 LSB	0.1784	0.1784	0.1906	99.99 %	-294.702	91057.3	-1.62668 LSB	-664.589 mLSB	1.61205 LSB	2.00597 LSB	1.487 LSB
418		P	-6.0 LSB	6.0 LSB	Bi-Modal (clear modes)	Samples	100281	7	0.01 %	19	-653.591 mLSB	5.52377 LSB	16.5713 LSB	-9.62881 LSB	1.67579 KLSB	0.3226	0.3226	0.4015	99.99 %	278.928	84611	-2.86343 LSB	-1.1848 LSB	2.19948 LSB	2.68483 LSB	1.99024 LSB
419		P	-25.0 LSB	25.0 LSB	Bi-Modal (clear modes)	Samples	100281	5	0.00 %	20	1.60475 LSB	10.5458 LSB	31.6373 LSB	-38.7511 LSB	1.78979 KLSB	0.7395	0.8409	0.7395	100.00 %	144.328	24389.2	-6.0801 LSB	-2.19948 LSB	8.37468 LSB	6.53394 LSB	4.84354 LSB
430		P	0.606 V	0.646 V	Gaussian	Samples	100268	0	0.00 %	21	626.945 mV	3.8123 mV	11.4369 mV	611.158 mV	643.302 mV	1.67	1.83	1.67	100.00 %	0.0219976	0.0317781	619.507 mV	626.936 mV	634.471 mV	5.13053 mV	3.80321 mV
431		P	0.623 V	0.67 V	Gaussian	Samples	100268	0	0.00 %	22	646.457 mV	3.82561 mV	11.4768 mV	630.531 mV	662.813 mV	2.04	2.04	2.05	100.00 %	0.0227774	0.0312783	639.008 mV	646.446 mV	654.015 mV	5.14644 mV	3.81501 mV
432		P	0.645 V	0.685 V	Gaussian	Samples	100268	0	0.00 %	23	665.973 mV	3.83312 mV	11.4994 mV	649.925 mV	682.267 mV	1.65	1.82	1.65	100.00 %	0.023244	0.0303011	658.514 mV	665.963 mV	673.55 mV	5.16403 mV	3.82804 mV
433		P	0.662 V	0.709 V	Gaussian	Samples	100268	0	0.00 %	24	685.484 mV	3.83494 mV	11.5048 mV	669.352 mV	701.86 mV	2.04	2.04	2.04	100.00 %	0.0229052	0.0287073	678.027 mV	685.473 mV	693.052 mV	5.16146 mV	3.82614 mV
434		P	0.684 V	0.724 V	Gaussian	Samples	100268	1	0.00 %	25	704.98 mV	3.84089 mV	11.5227 mV	634.017 mV	721.196 mV	1.65	1.82	1.65	100.00 %	-0.0415589	1.17165	697.511 mV	704.97 mV	712.539 mV	5.15902 mV	3.82433 mV
435		P	0.703 V	0.743 V	Gaussian	Samples	100268	1	0.00 %	26	724.489 mV	3.83893 mV	11.5168 mV	653.554 mV	740.698 mV	1.61	1.87	1.61	100.00 %	-0.0440728	1.17359	717.032 mV	724.477 mV	732.032 mV	5.15902 mV	3.82433 mV
436		P	0.723 V	0.763 V	Gaussian	Samples	100268	1	0.00 %	27	744.001 mV	3.83495 mV	11.5049 mV	673.126 mV	760.192 mV	1.65	1.83	1.65	100.00 %	-0.0452716	1.1709	736.53 mV	743.994 mV	751.537 mV	5.15604 mV	3.82212 mV
437		P	0.742 V	0.782 V	Gaussian	Samples	100268	1	0.00 %	28	763.533 mV	3.83037 mV	11.4911 mV	692.567 mV	779.777 mV	1.61	1.87	1.61	100.00 %	-0.0467892	1.18107	756.073 mV	763.528 mV	771.055 mV	5.15097 mV	3.81836 mV
438		P	0.762 V	0.802 V	Gaussian	Samples	100268	1	0.00 %	29	783.061 mV	3.84941 mV	11.5482 mV	634.009 mV	799.449 mV	1.64	1.82	1.64	100.00 %	-0.565143	22.3636	775.601 mV	783.062 mV	790.553 mV	5.14454 mV	3.81359 mV
439		P	0.781 V	0.821 V	Gaussian	Samples	100268	1	0.00 %	30	802.606 mV	3.84531 mV	11.5359 mV	653.519 mV	818.884 mV	1.59	1.87	1.59	100.00 %	-0.567223	22.4731	795.155 mV	802.602 mV	810.092 mV	5.13899 mV	3.80948 mV
440		P	0.801 V	0.841 V	Gaussian	Samples	100268	1	0.00 %	31	822.151 mV	3.84368 mV	11.5311 mV	673.077 mV	838.315 mV	1.63	1.83	1.63	100.00 %	-0.569694	22.5069	814.699 mV	822.155 mV	829.626 mV	5.13804 mV	3.80878 mV
441		P	0.82 V	0.86 V	Gaussian	Samples	100268	1	0.00 %	32	841.712 mV	3.84379 mV	11.5314 mV	692.639 mV	857.908 mV	1.59	1.88	1.59	100.00 %	-0.570649	22.4977	834.256 mV	841.716 mV	849.182 mV	5.13399 mV	3.80577 mV
Test	Name	Type	Low L.	High L.	Shape	Source	Execs	Fails	Fails %	Flow ID	Mean	Sigma	3xSigma	Min	Max	Cpk	Cpl	Cpu	Yield	Skew	Kurtosis	P2.5%	P50% - Median	P97.5%	IQR	IQR SD
442		P	0.84 V	0.88 V	Gaussian	Samples	100268	0	0.00 %	33	861.275 mV	3.81588 mV	11.4477 mV	845.201 mV	877.407 mV	1.64	1.86	1.64	100.00 %	0.00921444	0.0220939	853.812 mV	861.278 mV	868.748 mV	5.13452 mV	3.80617 mV
443		P	0.86 V	0.9 V	Gaussian	Samples	100268	0	0.00 %	34	880.856 mV	3.81952 mV	11.4586 mV	865.023 mV	897.058 mV	1.67	1.82	1.67	100.00 %	0.0082134	0.0220421	873.384 mV	880.861 mV	888.331 mV	5.13846 mV	3.80909 mV
444		P	0.879 V	0.919 V	Gaussian	Samples	100268	0	0.00 %	35	900.454 mV	3.8278 mV	11.4834 mV	884.462 mV	916.682 mV	1.62	1.87	1.62	100.00 %	0.00768267	0.0201306	892.959 mV	900.461 mV	907.943 mV	5.15097 mV	3.81836 mV
445		P	0.899 V	0.939 V	Gaussian	Samples	100268	0	0.00 %	36	920.065 mV	3.8402 mV	11.5206 mV	904.083 mV	936.422 mV	1.64	1.83	1.64	100.00 %	0.00839755	0.0206975	912.541 mV	920.071 mV	927.568 mV	5.17395 mV	3.83542 mV
446		P	0.29 V	0.297 V	Gaussian	Samples	100268	0	0.00 %	37	293.121 mV	588.601 uV	1.7658 mV	290.49 mV	295.711 mV	1.77	1.77	2.20	100.00 %	-0.0036459	0.00746272	291.963 mV	293.121 mV	294.27 mV	790.507 uV	585.995 uV
447		P	-0.5 LSB	0.5 LSB	Bi-Modal (clear modes)	Samples	100268	7	0.01 %	38	11.4251 mLSB	453.008 mLSB	1.35902 LSB	-16.0315 LSB	127.601 LSB	0.3595	0.3763	0.3595	99.99 %	221.962	62822.4	-269.697 mLSB	100.327 mLSB	274.119 mLSB	331.449 mLSB	245.7 mLSB
448		P	-1.0 LSB	1.0 LSB	Bi-Modal (clear modes)	Samples	100268	5	0.00 %	39	-229.164 mLSB	452.039 mLSB	1.35612 LSB	-127.9 LSB	527.163 mLSB	0.5684	0.5684	0.9064	100.00 %	-226.359	63522.5	-500.737 mLSB	-253.48 mLSB	221.239 mLSB	163.063 mLSB	120.877 mLSB
460		P	0.606 V	0.646 V	Gaussian	Samples	100261	0	0.00 %	40	626.944 mV	3.81234 mV	11.437 mV	611.158 mV	643.302 mV	1.67	1.83	1.67	100.00 %	0.022071	0.0317485	619.507 mV	626.935 mV	634.471 mV	5.13148 mV	3.80392 mV
461		P	0.607 V	0.647 V	Gaussian	Samples	100261	0	0.00																	





Part Average Testing



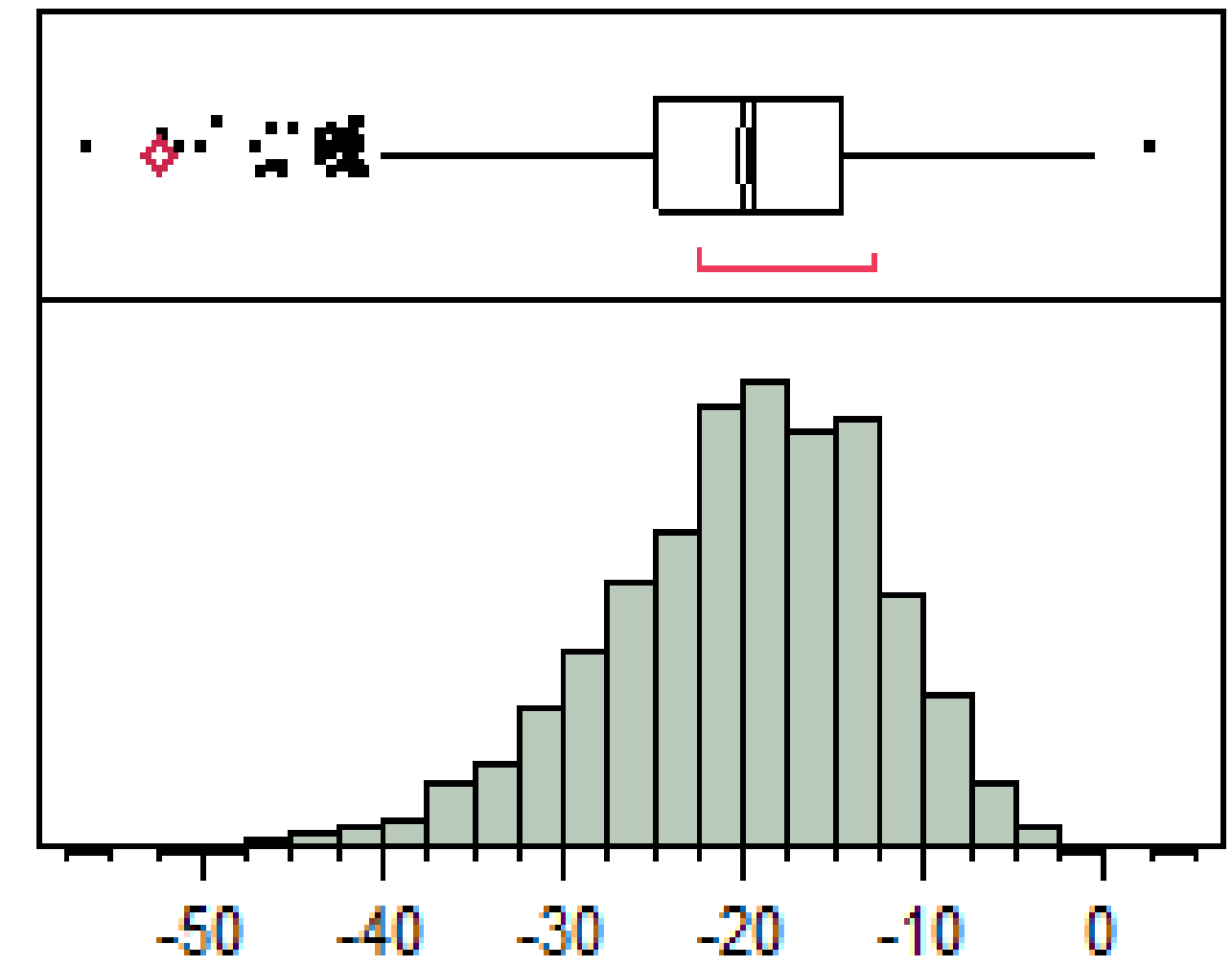
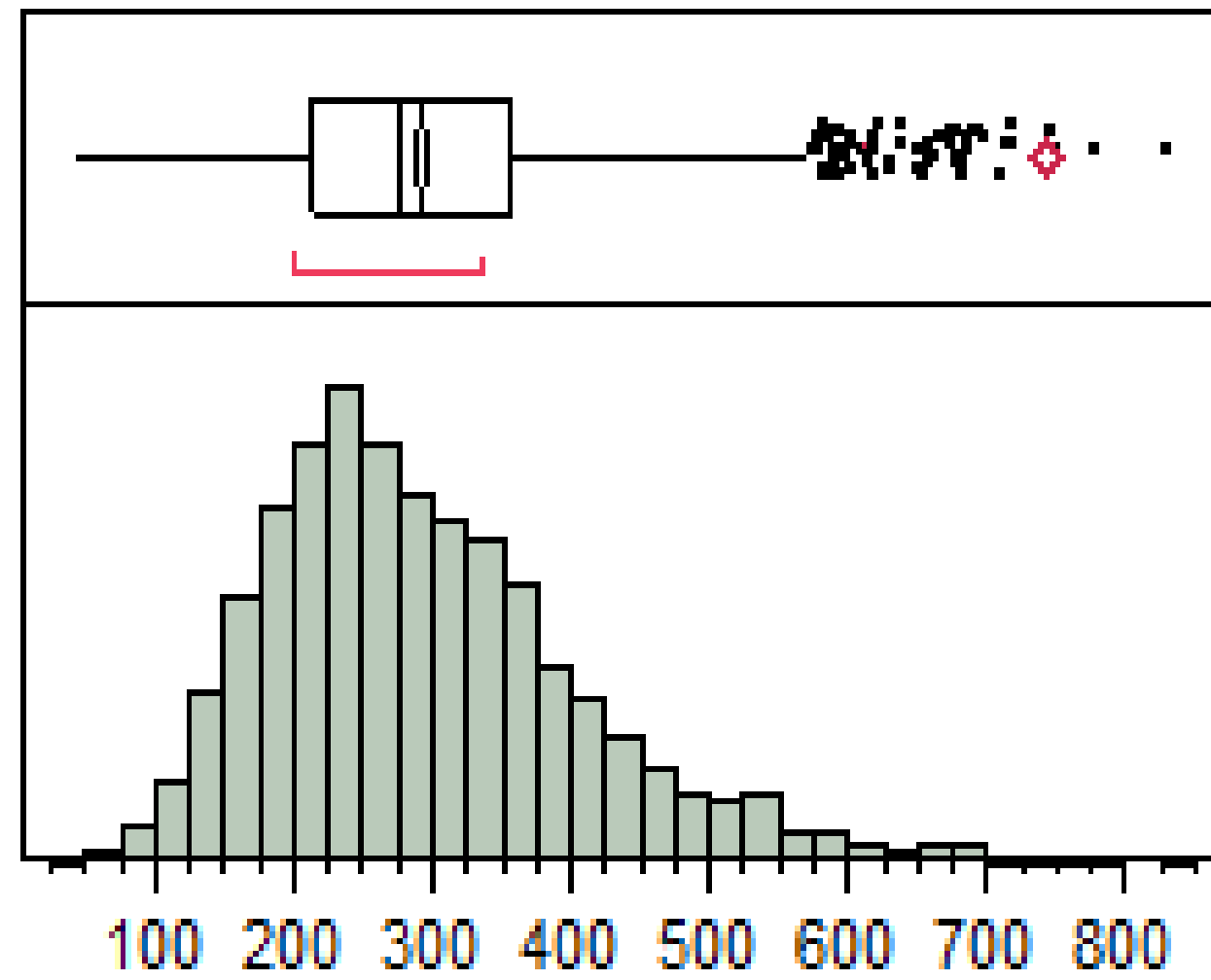
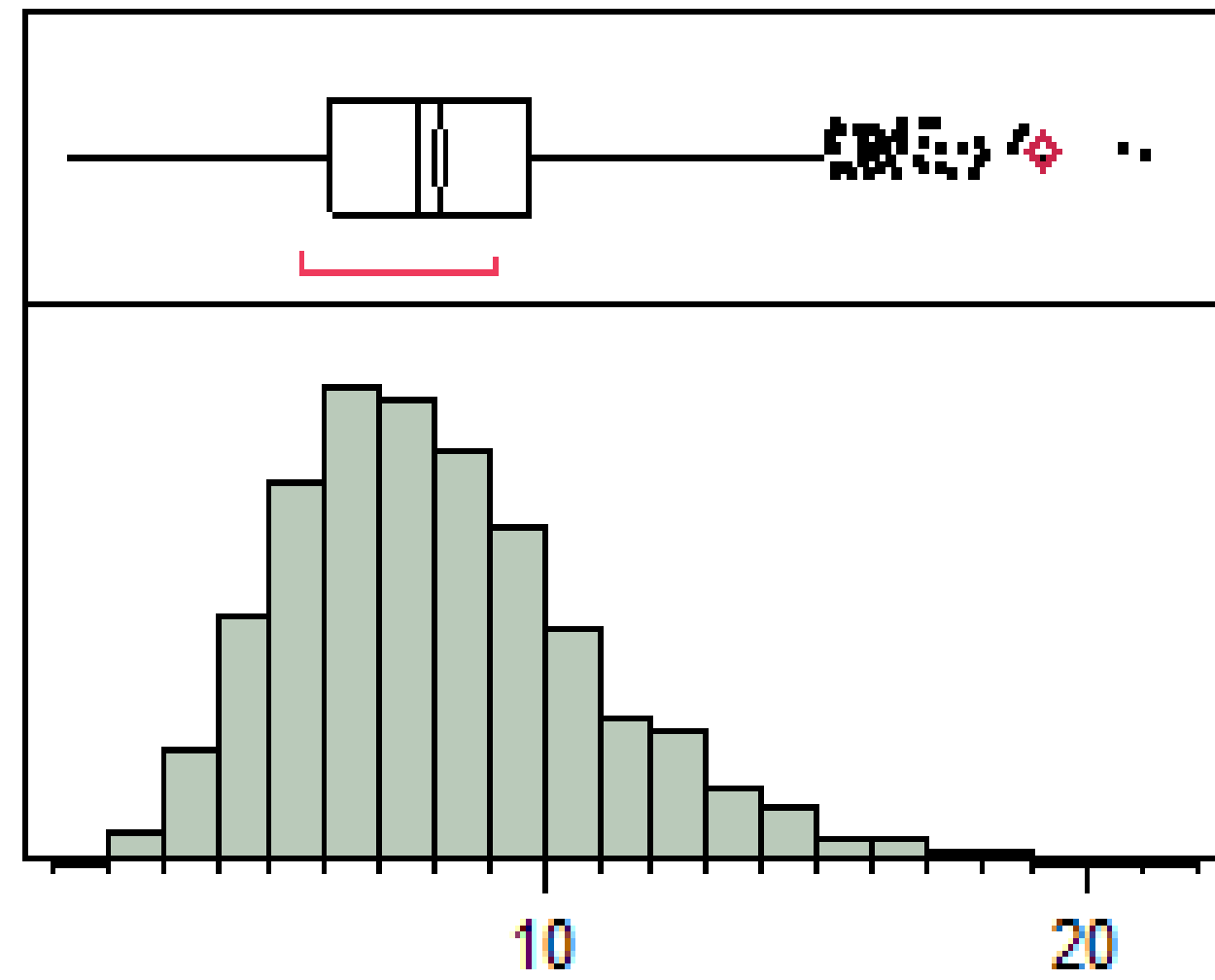
Method	Results (out of 50)	Yield Hit
DPAT Production Rule Set	0	0

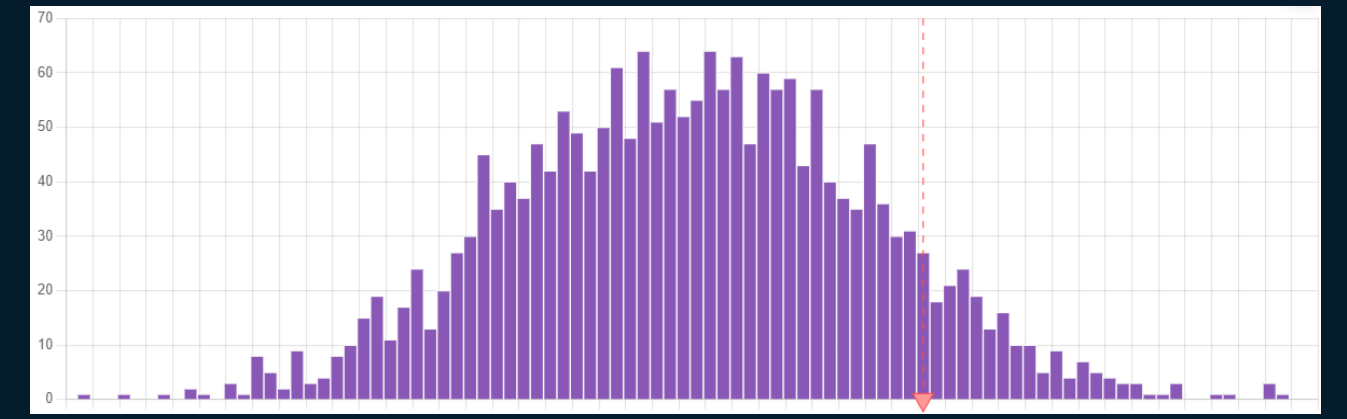
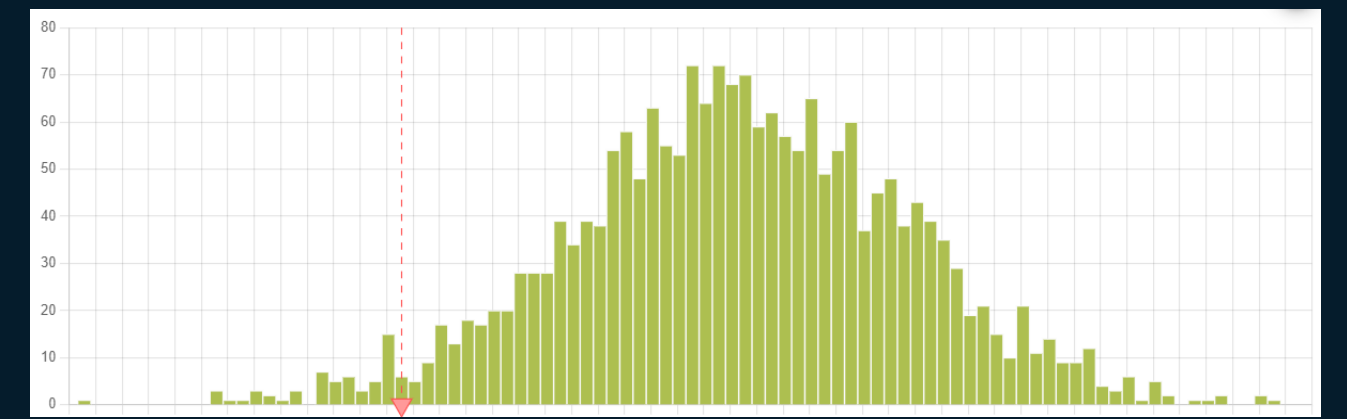
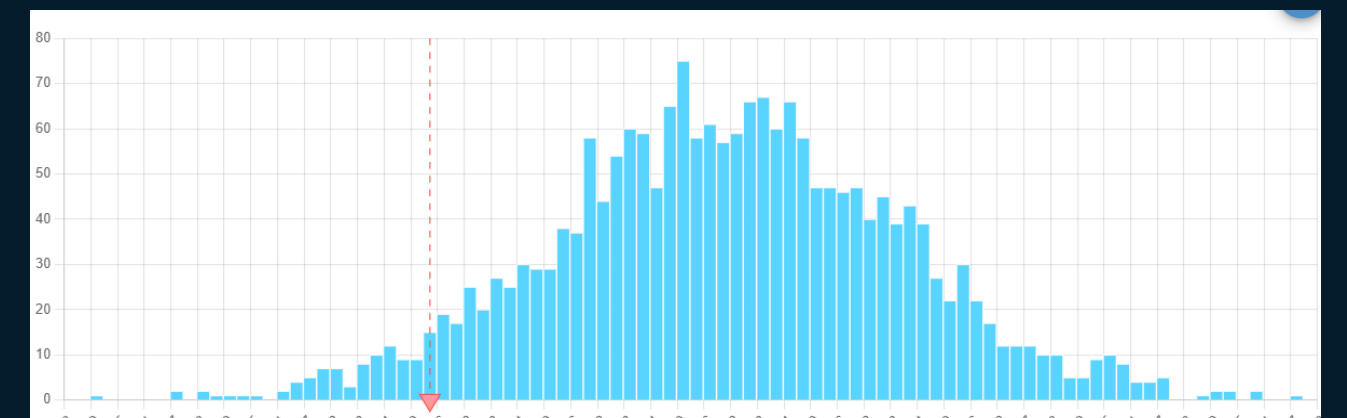
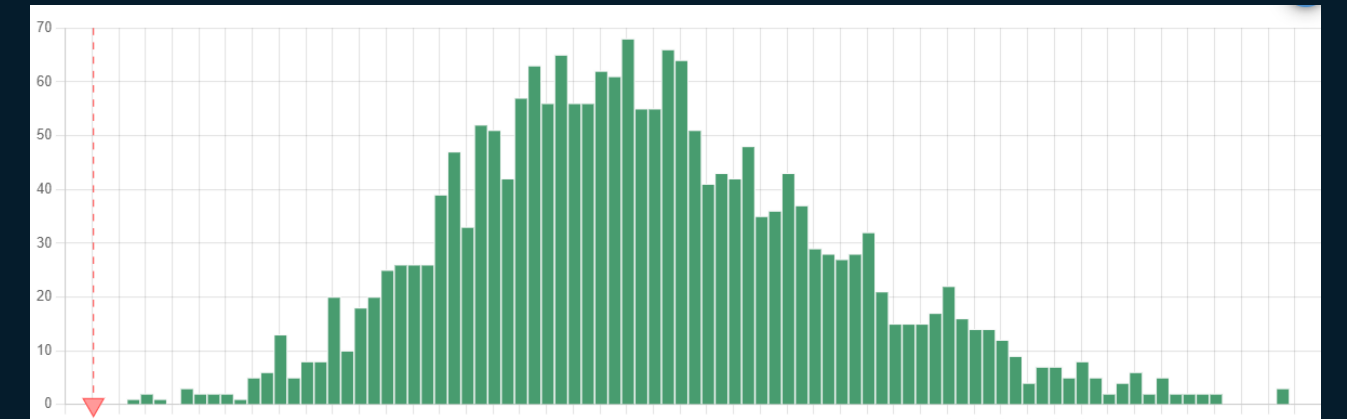
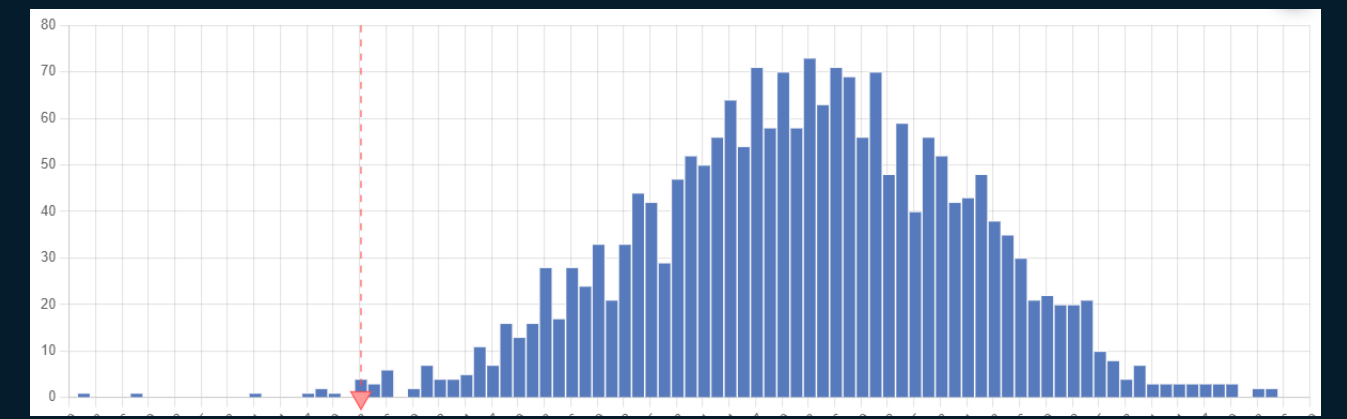
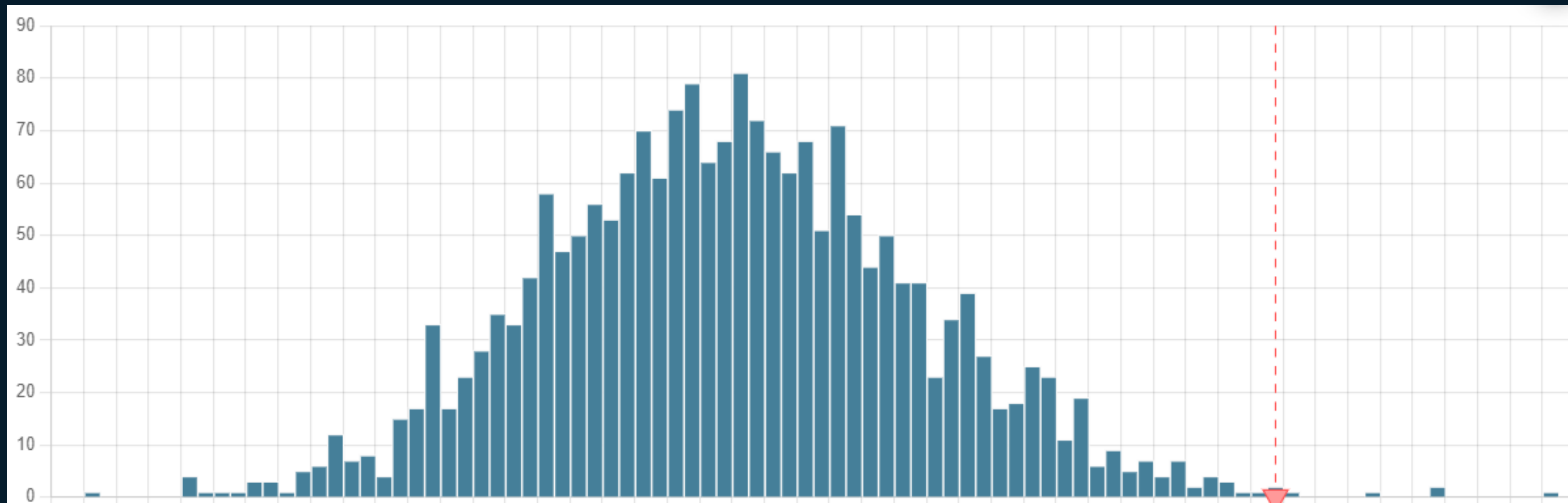
Method	Results (out of 50)	Yield Hit
DPAT Production Rule Set	0	0
DPAT Aggressive	0	0.9%

Method	Results (out of 50)	Yield Hit
DPAT Production Rule Set	0	0
DPAT Aggressive	0	0.9%
DPAT More Aggressive	1	12.6%

Multivariate Methods.

What is a multivariate outlier?





Method	Results (out of 50)	Yield Hit
DPAT Production Rule Set	0	0
DPAT Aggressive	0	0.9%
DPAT More Aggressive	1	12.6%
MultiVariable 1 : Z(σ) Stacking	8	3%



US007305723B2

(12) **United States Patent**
Fulks

(10) **Patent No.:** US 7,305,723 B2
(45) **Date of Patent:** Dec. 11, 2007

(54) **KITCHEN SINK WITH INTEGRATED CUTTING BOARD**

5,313,676 A 5/1994 Wright
5,406,656 A 4/1995 Somerton

(76) Inventor: **J**
C

(*) Notice: **S**
p
U

(21) Appl. No.: I

(22) Filed: A

(65)

US 2007/004

(51) **Int. Cl.**

E03C 1/33

(52) **U.S. Cl.**

(58) **Field of Cla**

See applicati

(56)

U.S.

2,194,343 A *

2,308,123 A

2,314,157 A

2,334,293 A

2,579,393 A

2,658,205 A

3,346,886 A

3,625,162 A

4,041,964 A

4,305,166 A

4,456,021 A

4,765,603 A

5,016,298 A

United States Patent

Macedo

[19]

[11]

Patent Number: 5,855,027

[45]

Date of Patent: Jan. 5, 1999

[54] **AUTOMATIC BATHROOM DOOR AND TOILET FLUSHING SYSTEM**

2,909,718 10/1959 Lawick 49/25
3,056,143 10/1962 Foster 4/DIG. 3
4,707,867 11/1987 Kwashe et al. 4/313

[76] Inventor: .

[21] Appl. No.:

[22] Filed:

[51] **Int. Cl.**

[52] **U.S. Cl.**

[58] **Field of Se**

[56]

U.S.

1,830,405 11/

2,019,084 10/

2,499,889 3/

2,786,210 3/

IO

(12) **United States Patent**

Tiwari et al.

(10) **Patent No.:** US 10,606,963 B2

(45) **Date of Patent:** Mar. 31, 2020

(54) **SYSTEM AND METHOD FOR CAPTURING AND ANALYZING MULTIDIMENSIONAL BUILDING INFORMATION**

(71) Applicant: **Carrier Corporation**, Farmington, CT (US)

(72) Inventors: **Ankit Tiwari**, Burlington, MA (US);

Kushal Mukherjee, Cork (IE); **Sofiane**

Yous, Cork (IE); **Rodolfo De Paz**

Alberola, Cork (IE); **Berta Carballido**

Villaverde, Cork (IE); **Vijaya**

Ramaraju Lakamraju, Farmington,

CT (US); **Pedro Orellana Fernandez**,

Vigo (ES); **Craig R. Walker**, South

Glastonbury, CT (US)

(73) Assignee: **Carrier Corporation**, Palm Beach

Gardens, FL (US)

(*) Notice: Subject to any disclaimer, the term of this

patent is extended or adjusted under 35

U.S.C. 154(b) by 0 days.

(21) Appl. No.: 15/560,370

(22) PCT Filed: Mar. 23, 2016

(86) PCT No.: PCT/US2016/023774

§ 371 (c)(1), Sep. 21, 2017

(87) PCT Pub. No.: WO2016/154306

PCT Pub. Date: Sep. 26, 2016

(65) **Prior Publication Data**

US 2018/0075168 A1 Mar. 15, 2018

Related U.S. Application Data

(60) Provisional application No. 62/137,452, filed on Mar.

24, 2015.

(51) **Int. Cl.**

G06K 9/00 (2006.01)

G06F 17/50 (2006.01)

(Continued)

(52) **U.S. Cl.**

CPC **G06F 17/5004** (2013.01); **G06T 3/0068**

(2013.01); **G06T 7/0004** (2013.01);

(Continued)

(58) **Field of Classification Search**

CPC G06T 2207/30184

See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

5,668,562 A 9/1997 Cutrer et al.

5,831,610 A 11/1998 Tonelli et al.

(Continued)

FOREIGN PATENT DOCUMENTS

CN 101763656 A 6/2010

CN 103440526 A 12/2013

(Continued)

OTHER PUBLICATIONS

"3rd Generation Partnership Project: Technical Specification Group

Core Network and Terminals; Proximity-services (ProSe) User

Equipment (UE) to Proximity-services (ProSe) Function Protocol

aspects: Stage 3 (Release 12)" 3GPP Standard: 3GPP TS 24.334,

3rd Generation Partnership Project (3GPP), Mobile Competence

Center, 650, Route Des Lucioles, F-06921 Sophia-Antipolis Cedex,

France, vol. CT WGI, No. V1.0, Aug. 25, 2014, pp. 1-59, XP050774727.

(Continued)

Primary Examiner—Oneal R Mistry

(74) **Attorney, Agent, or Firm**—Locke Lord LLP; Scott

D. Wofsy; Judy R. Naamat

(57) **ABSTRACT**

A method for capturing building information includes capturing

dimensions of a 360 degree image at a first location

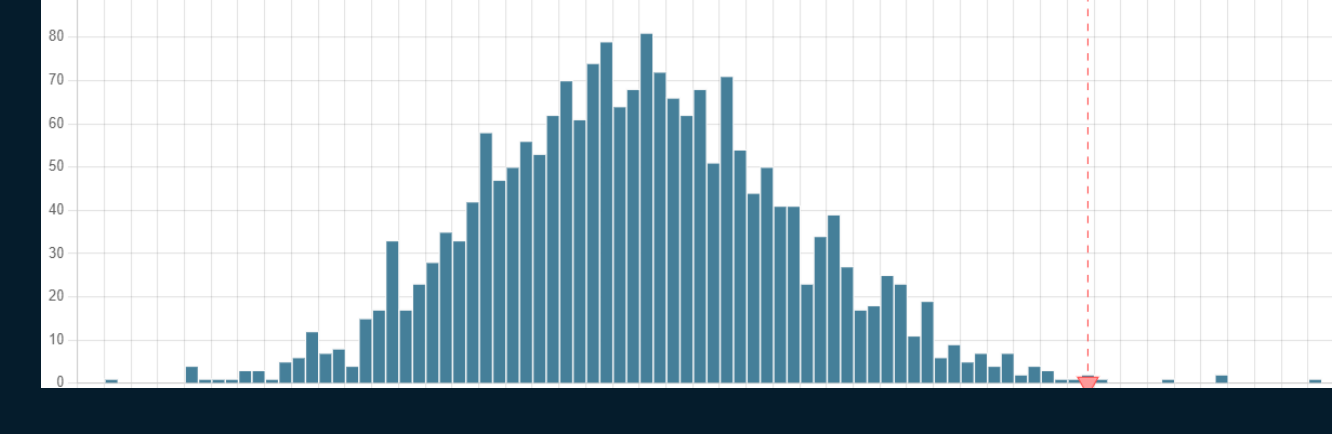
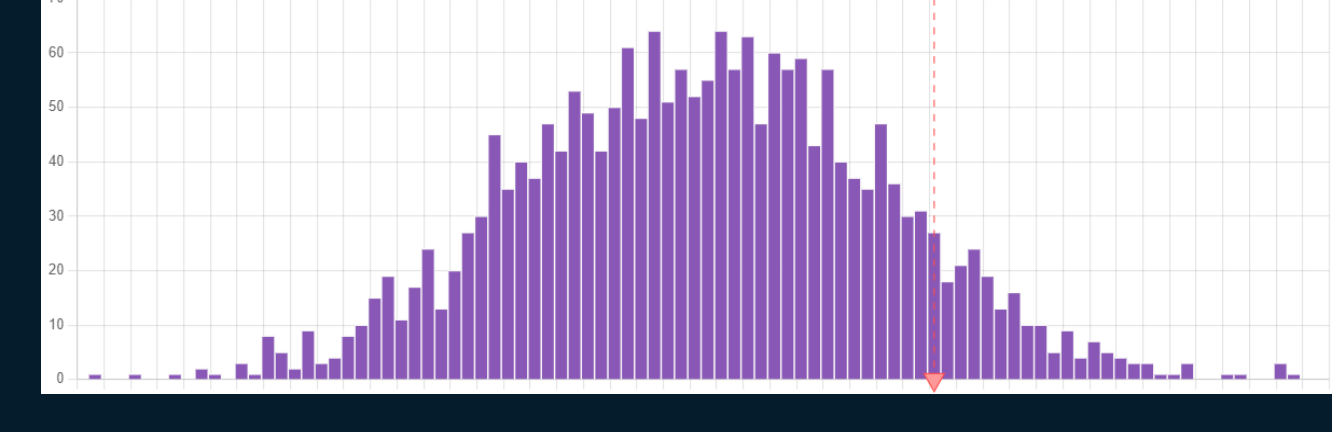
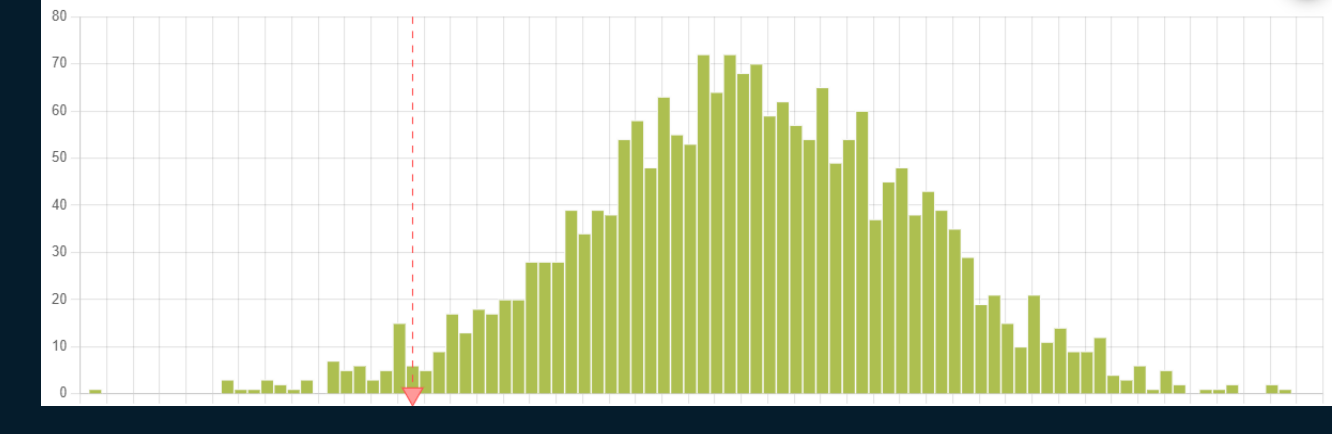
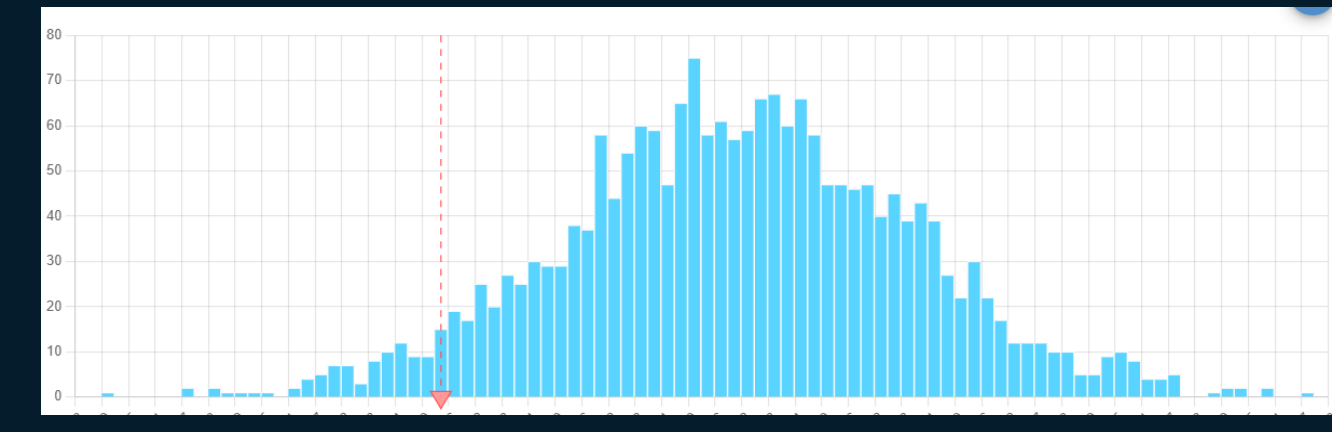
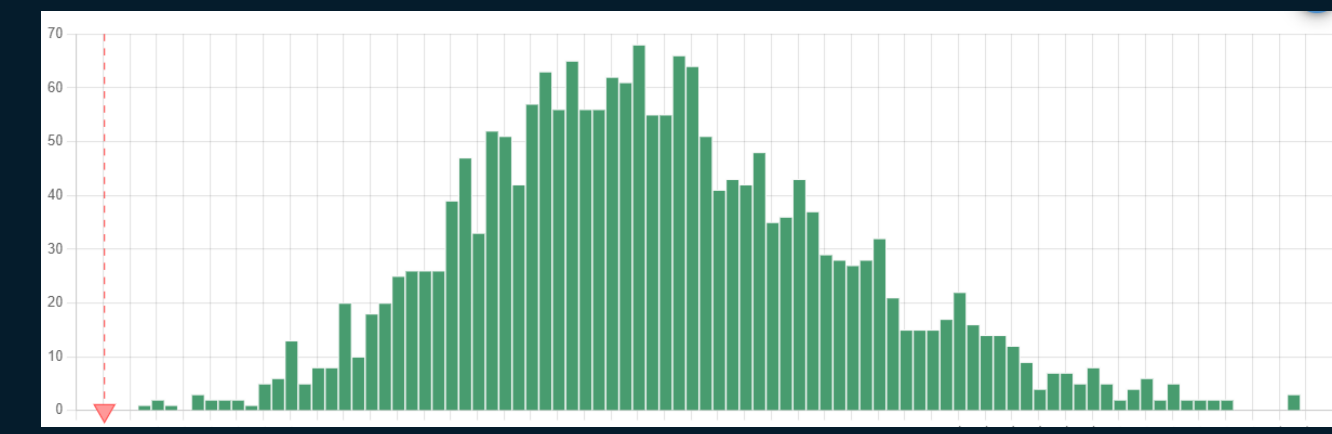
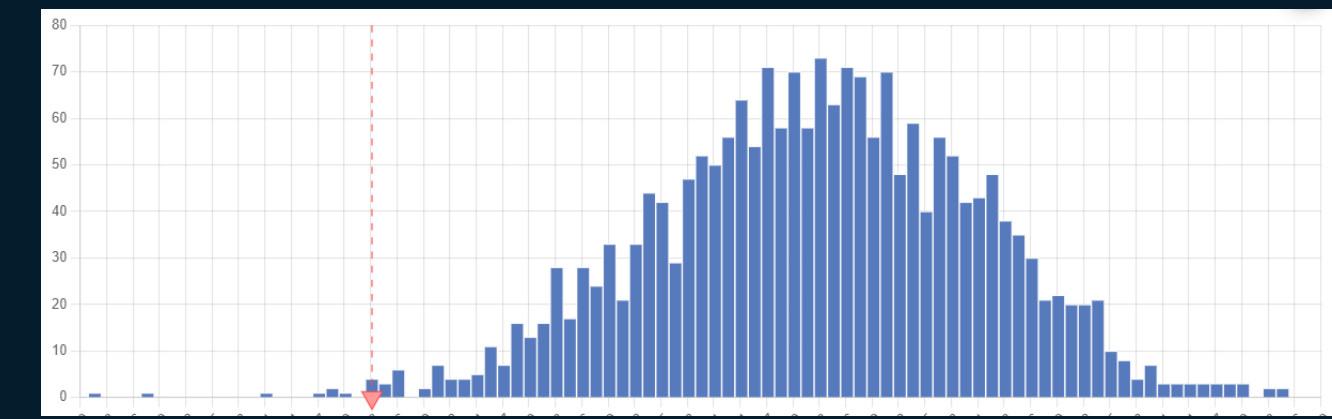
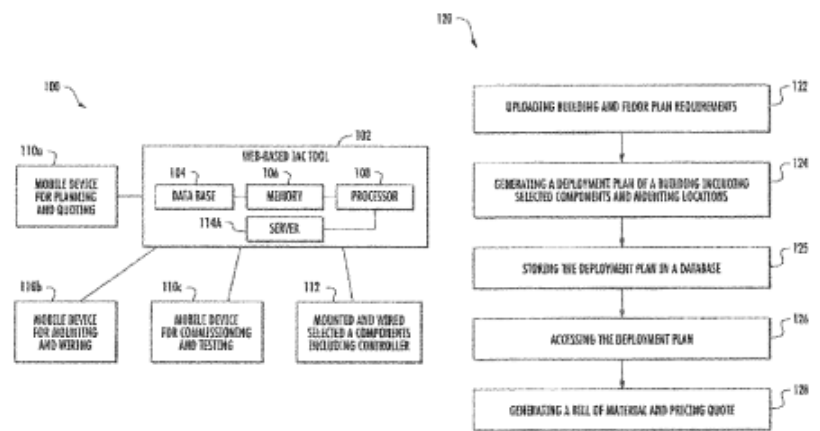
within a room of a building using a mobile device equipped

with at least direction sensor and at least one motion sensor.

The step of capturing dimensions is repeated within at least

one additional room. The mobile device receives user input

(Continued)



And now a word from our sponsor...



LOTNETWORK®

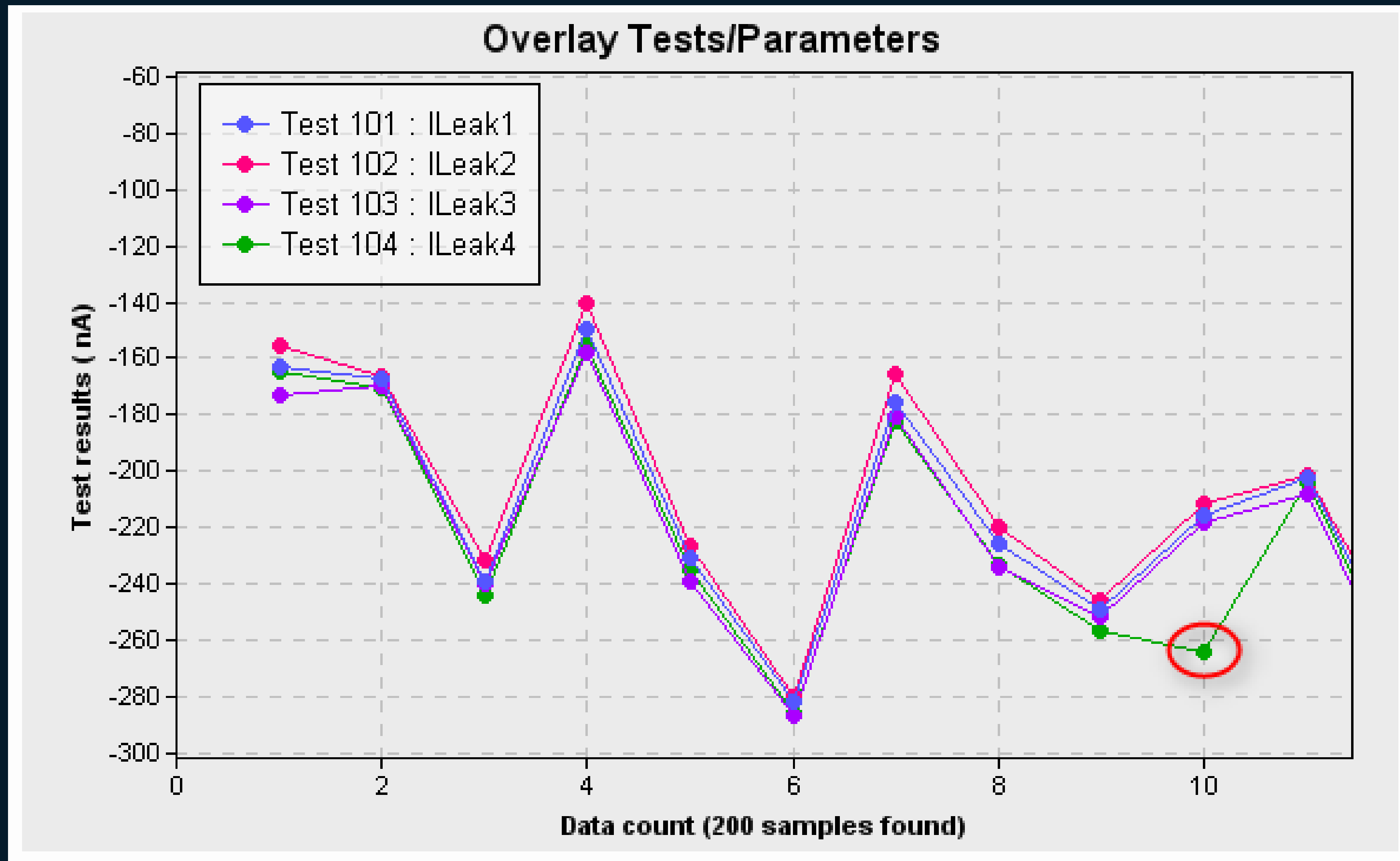
Protection Against Patent Assertion Entities

2,250+ Members
 3.5+ million assets
 >15% of all US patents

First Year Free For Galaxy Customers!

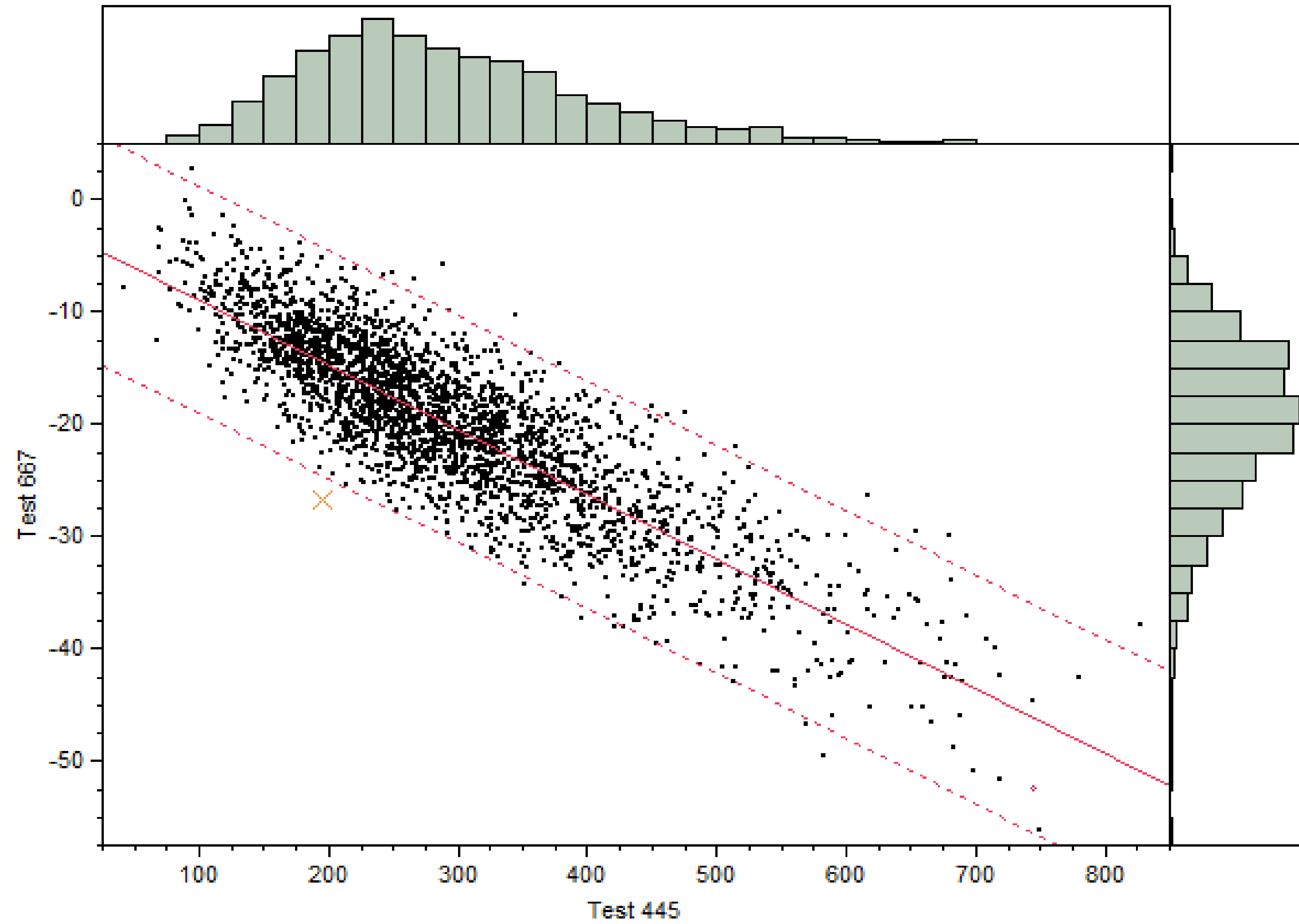


Correlations?



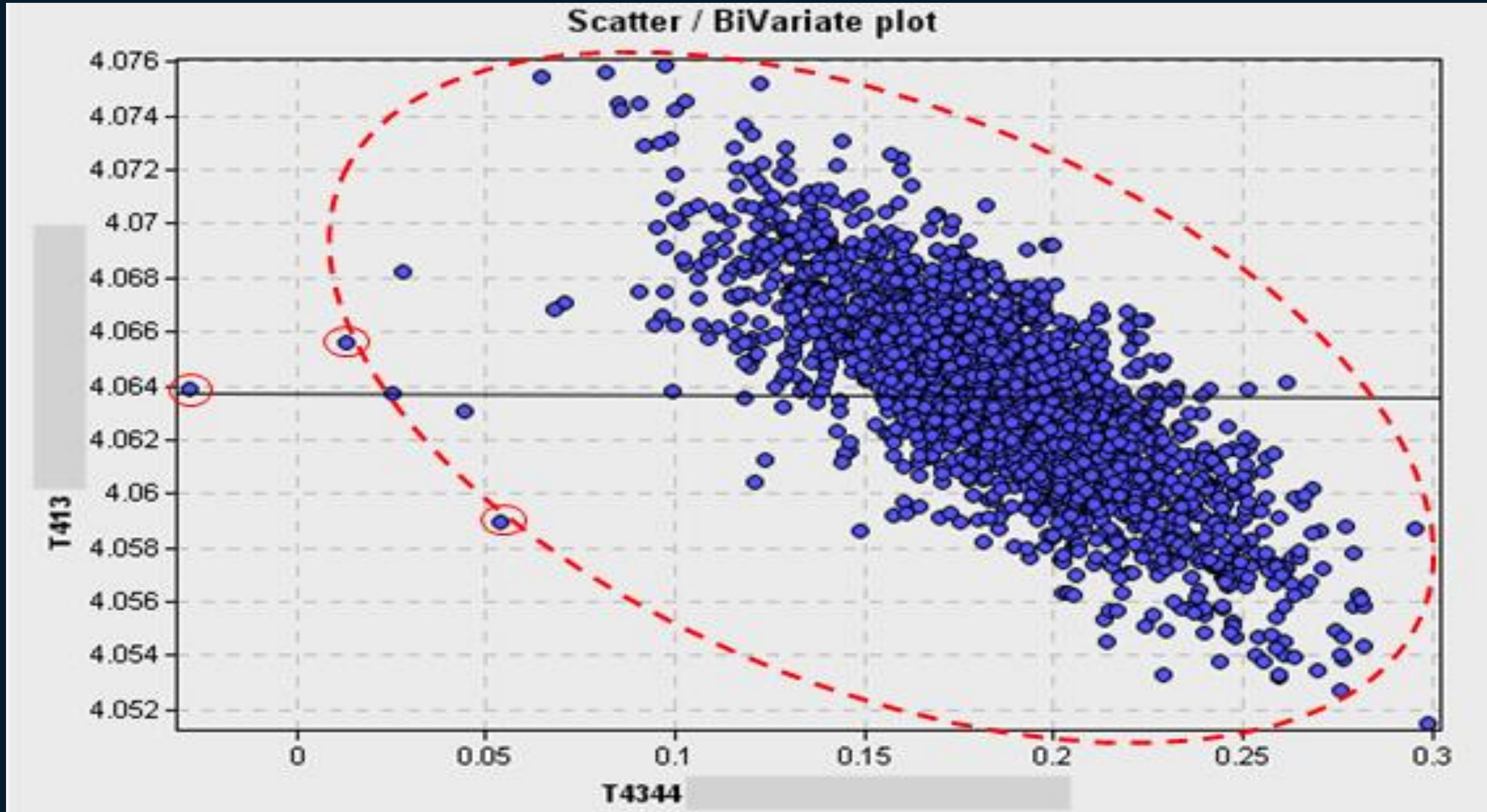
Leblond, Nicolas & Jochen Stephan. "Multi-Variate Part-Average-Testing Analysis to Improve Outlier Identification." Semicon Europa 2014. Grenoble, France Oct 2014

Correlations?



Correlations?

$$y = \pm \frac{b}{a} \sqrt{a^2 - x^2} = \pm \sqrt{(a^2 - x^2) (1 - e^2)}$$

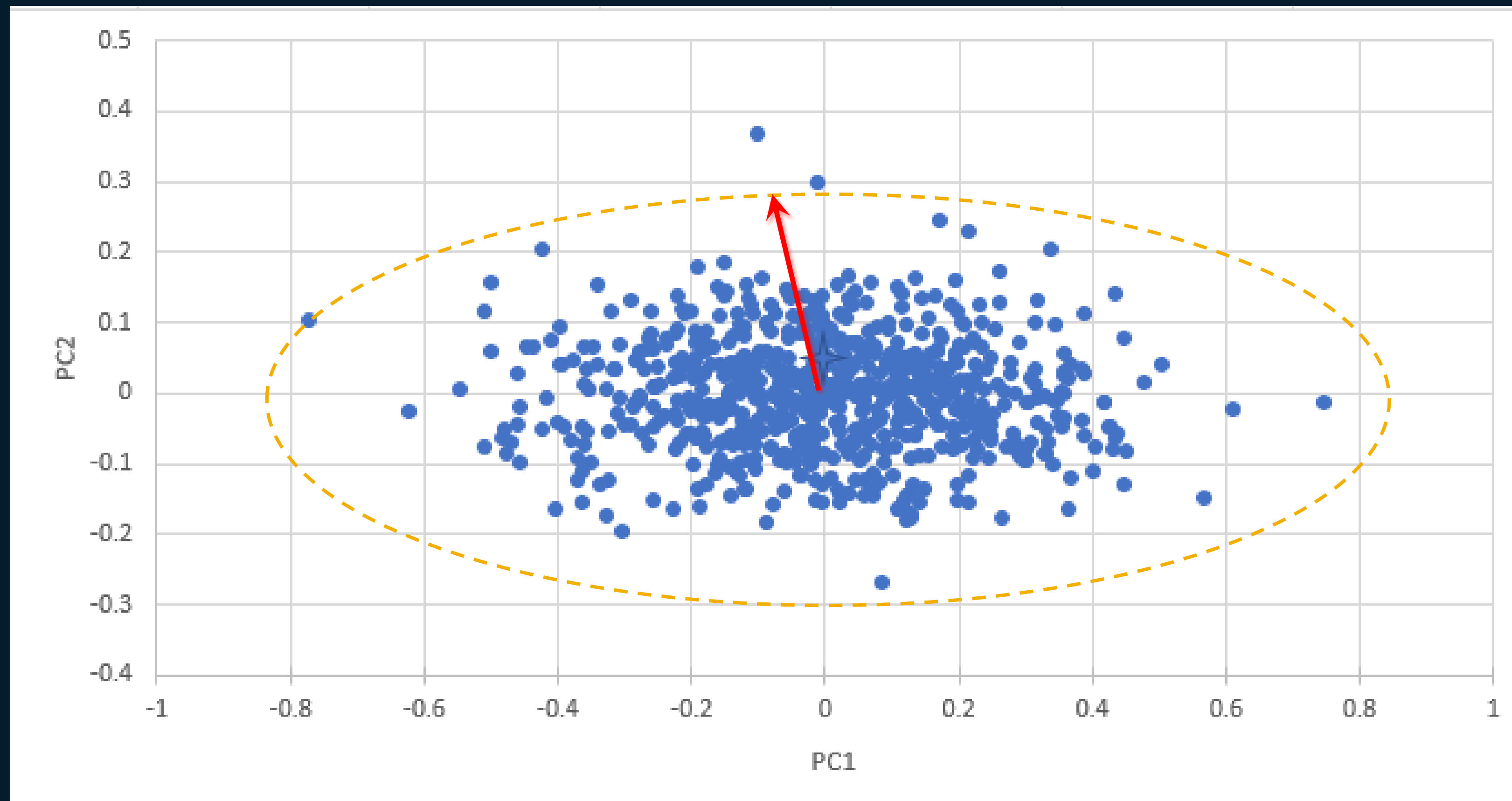


Method	Results (out of 50)	Yield Hit
DPAT Production Rule Set	0	0
DPAT Aggressive	0	0.9%
DPAT More Aggressive	1	12.6%
MultiVariable 1 : Z(σ) Stacking	8	3%
MultiVariable 2 : MV-PAT; Pearson Correlation	21	5.5%

Covariance Matrices, Mahalanobis Distance, and PCA?

(and an Oxford Comma)

$$D^2 = (x - m)^T \cdot C^{-1} \cdot (x - m) *$$



* Cansiz, S. (2022, January 26). *Mahalanobis Distance and Multivariate Outlier Detection in R*. <https://towardsdatascience.com/mahalanobis-distance-and-outlier-detection-in-r-cb9c37576d7d>

Method	Results (out of 50)	Yield Hit
DPAT Production Rule Set	0	0
DPAT Aggressive	0	0.9%
DPAT More Aggressive	1	12.6%
MultiVariable 1 : Z(σ) Stacking	8	3%
MultiVariable 2 : MV-PAT Pearson Correlation	21	5.5%
MultiVariable 3 : PCA & Mahanalobis Distance	24	4.4%
MultiVariable 4: Same as above, more aggressive	27	13.1%

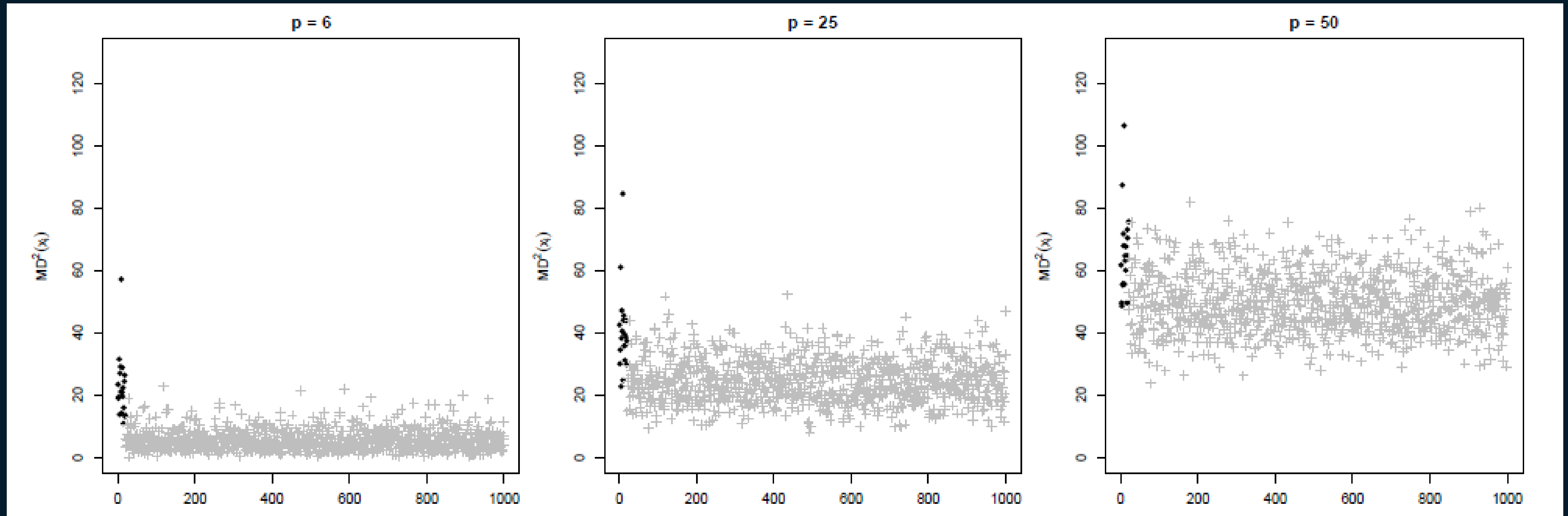
Problem: The objective of Principal Component Analysis is not outlier detection.

By definition, outliers may be lost.



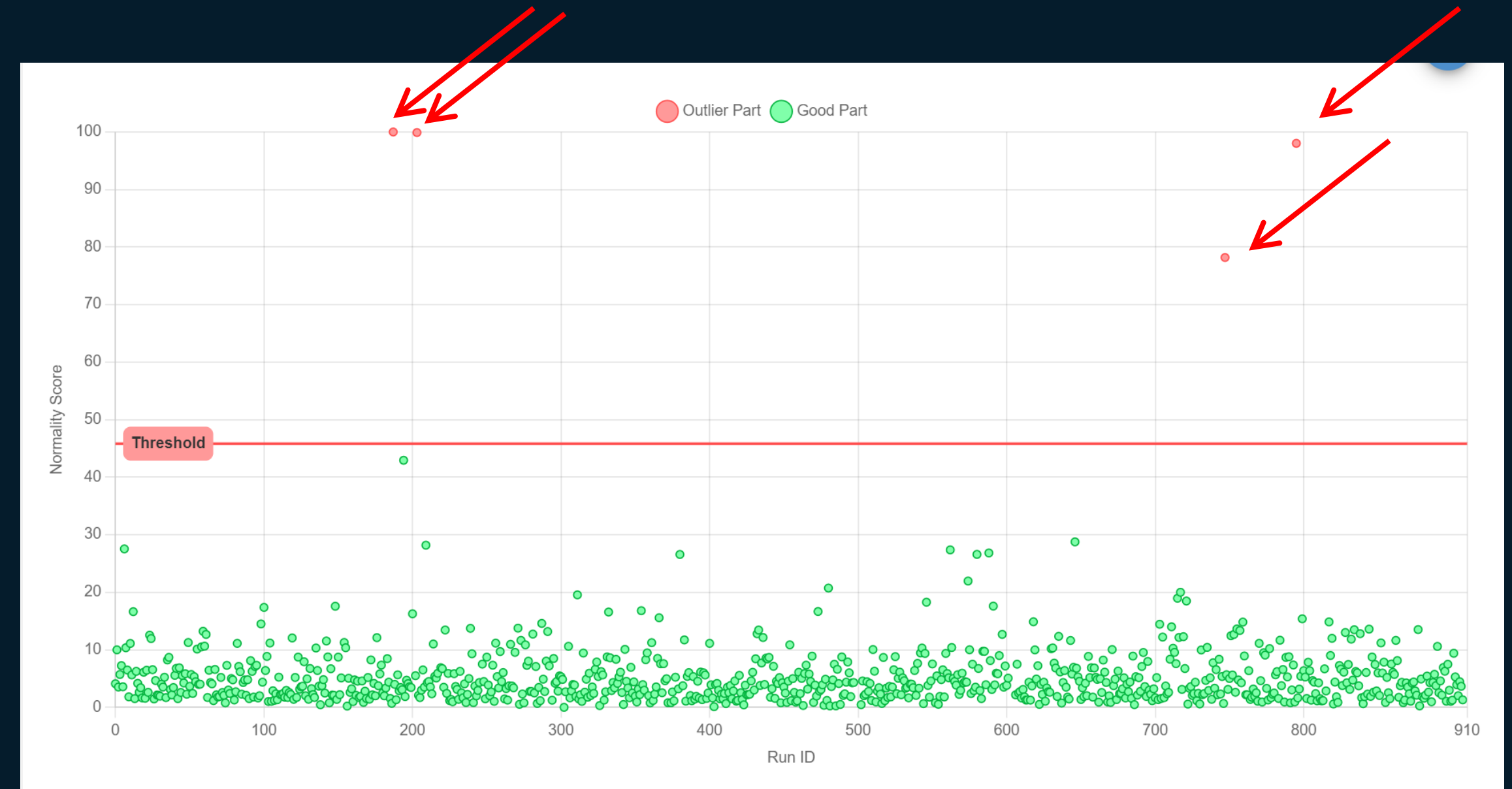
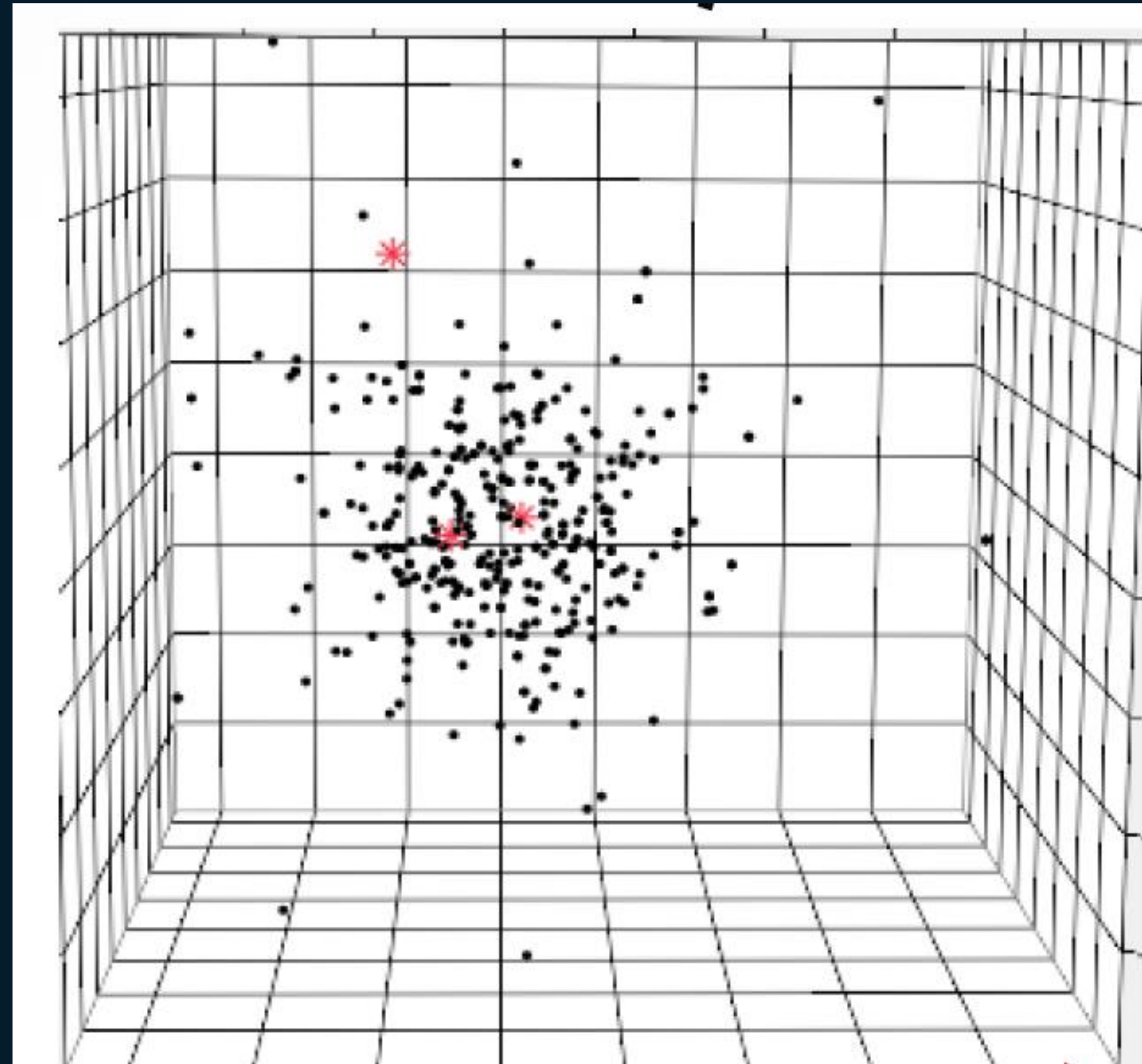
Another Problem: Mahalanobis distance performs poorly as p increases.*

Distributions approach Gaussian as p increases, reducing signal in the noise. (These data have $p=1,156$).

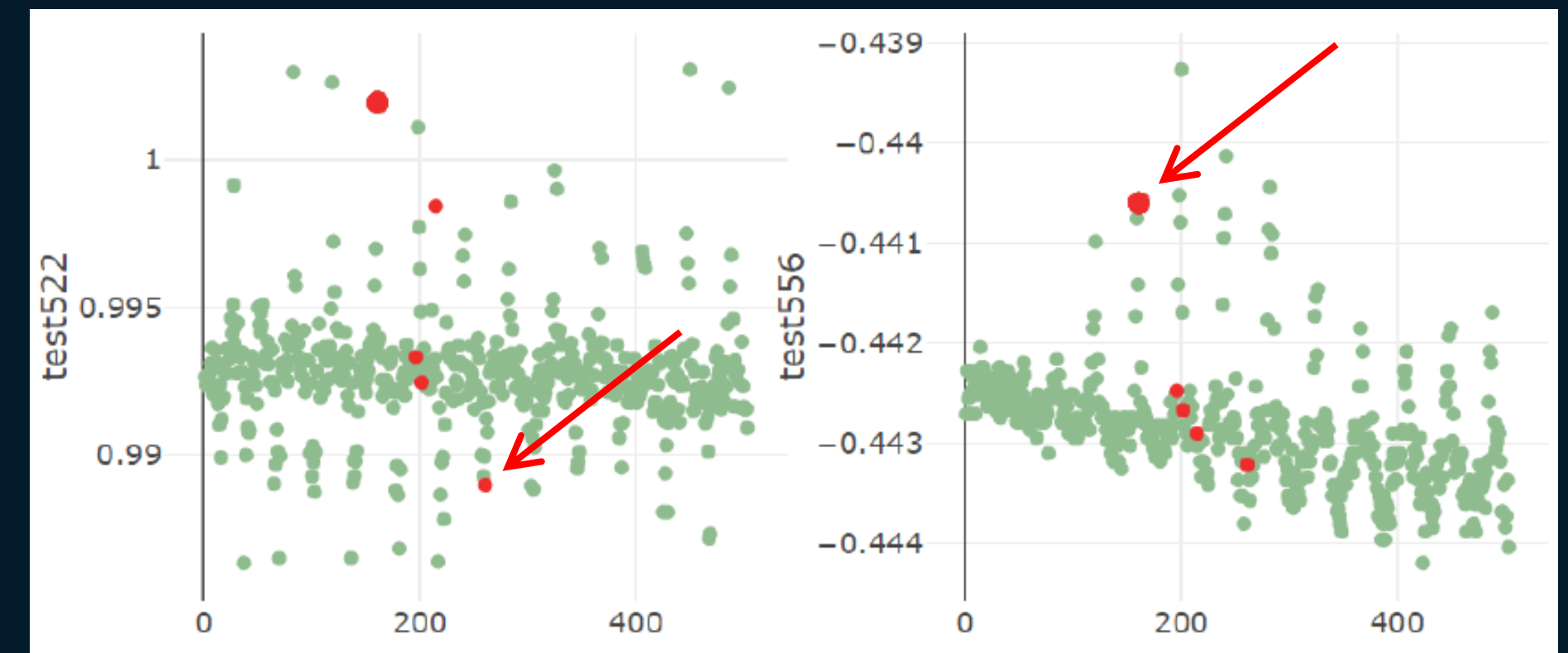
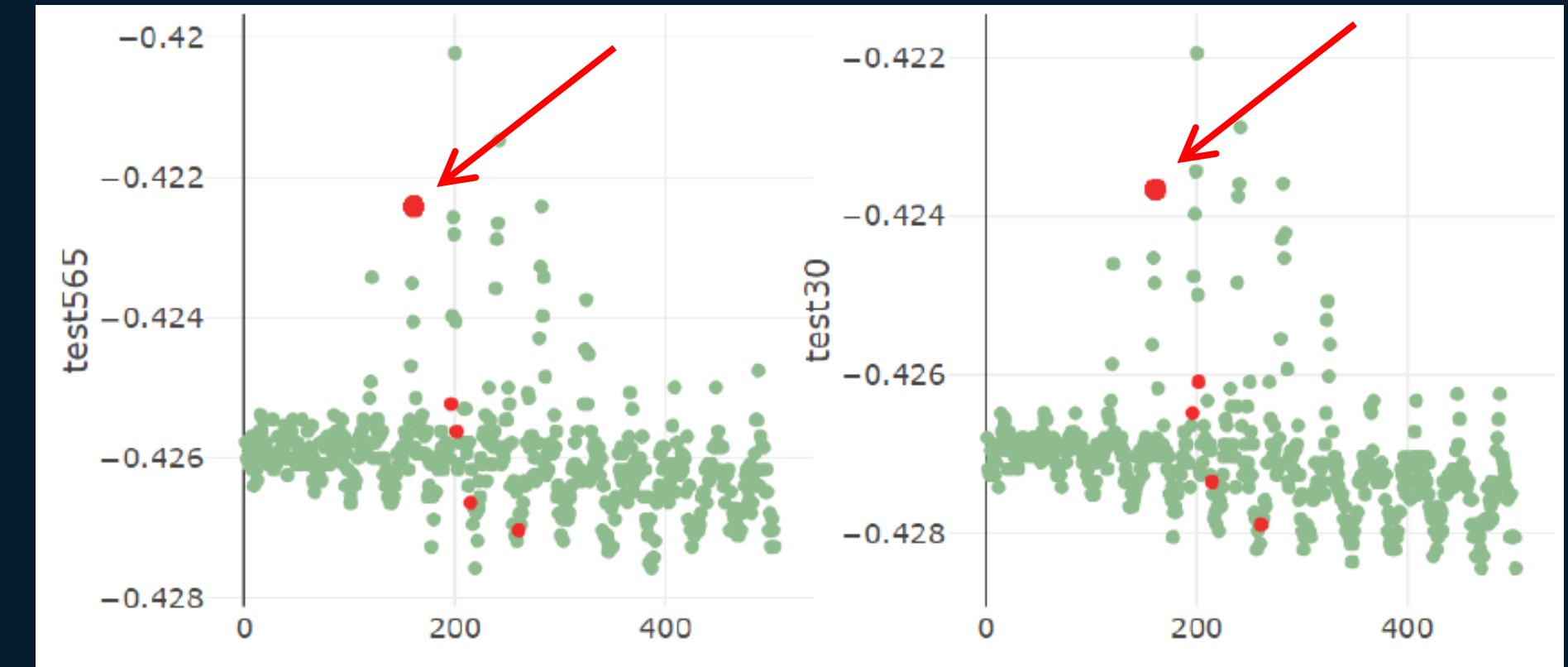
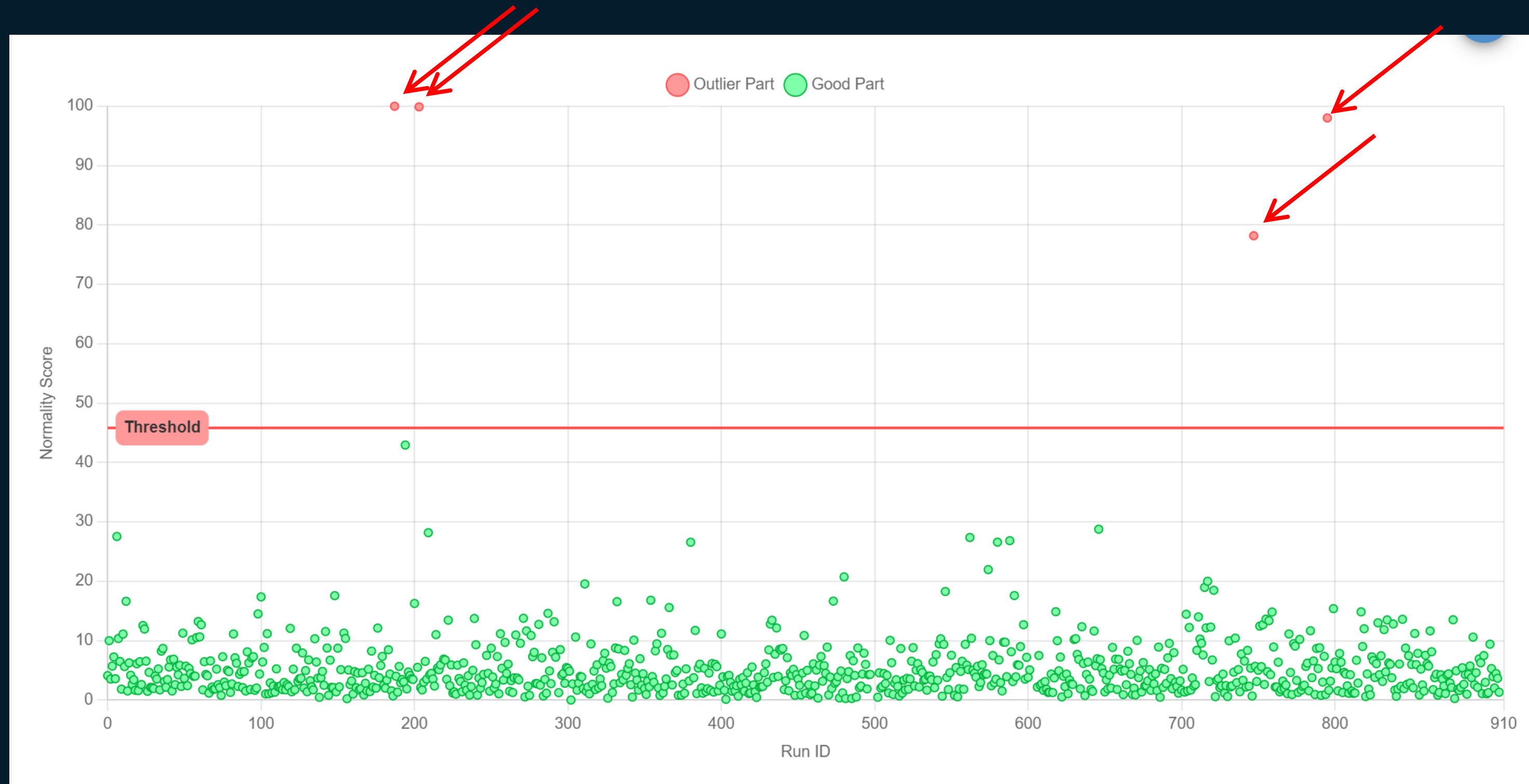


* Alessandrino, S., et al; (ST Microelectronics & Ippon Innovation) *From Space to Automotive: Advanced Detection of Burn-in Rejects on SiC Products Using a New Statistical Screening Approach.* Automotive Reliability & Test Europe. 5 Feb, 2021

A new method: *Orion* by Galaxy



A new method: *Orion* by Galaxy



* Ibid



Best results achieved by:

- Run traditional DPAT at relatively loose settings. (I.e: 9σ for Gaussian)
- Run Orion Omnivariate on remaining good die that did not fail the above methods.

Not tested in this experiment:

- Run NNR using typical settings with site-bias correction.
- Run GPAT to capture Good Die in Bad Neighborhood.

Method	Results (out of 50)	Yield Hit
DPAT Production Rule Set	0	0
DPAT Aggressive	0	0.9%
DPAT More Aggressive	1	12.6%
MultiVariable 1 : Z(σ) Stacking	8	3%
MultiVariable 2 : MV-PAT using Pearson Correlation	21	5.5%
MultiVariable 3 : PCA & Mahanalobis Distance	24	4.4%
MultiVariable 4: Same as above more aggressive	27	13.1%
Orion Omnivariate	44[*]	2.4%[*]

** Your mileage may vary.*

Thank You!

More info?

info@galaxysemi.com